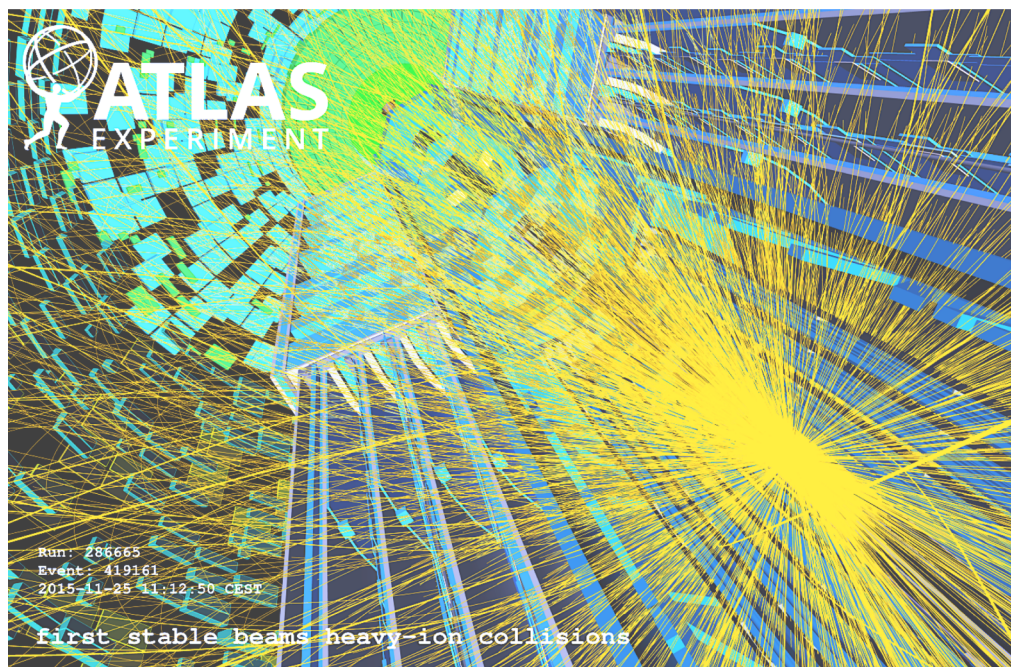


Operational Experience and Performance with the ATLAS Pixel detector at the LHC



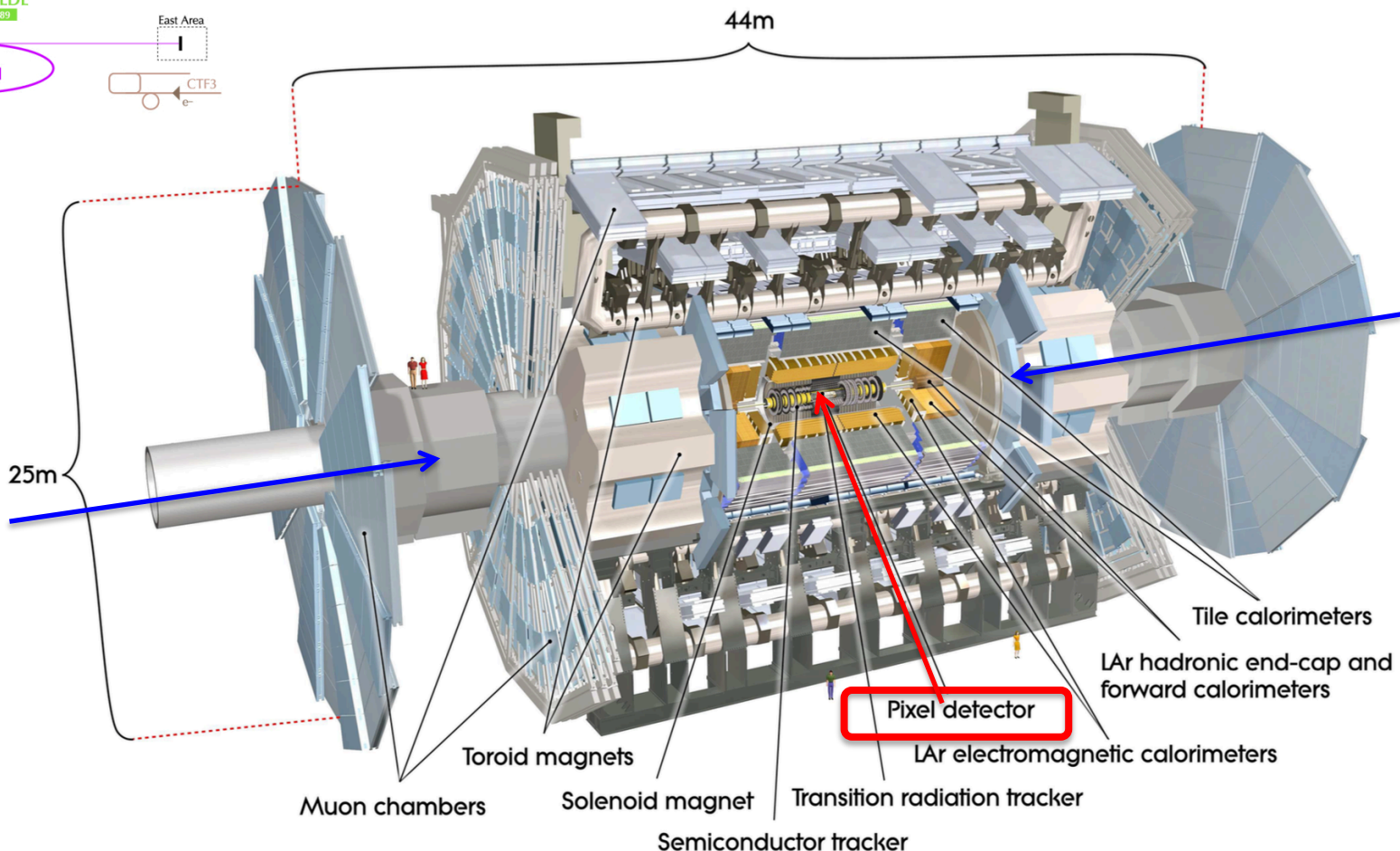
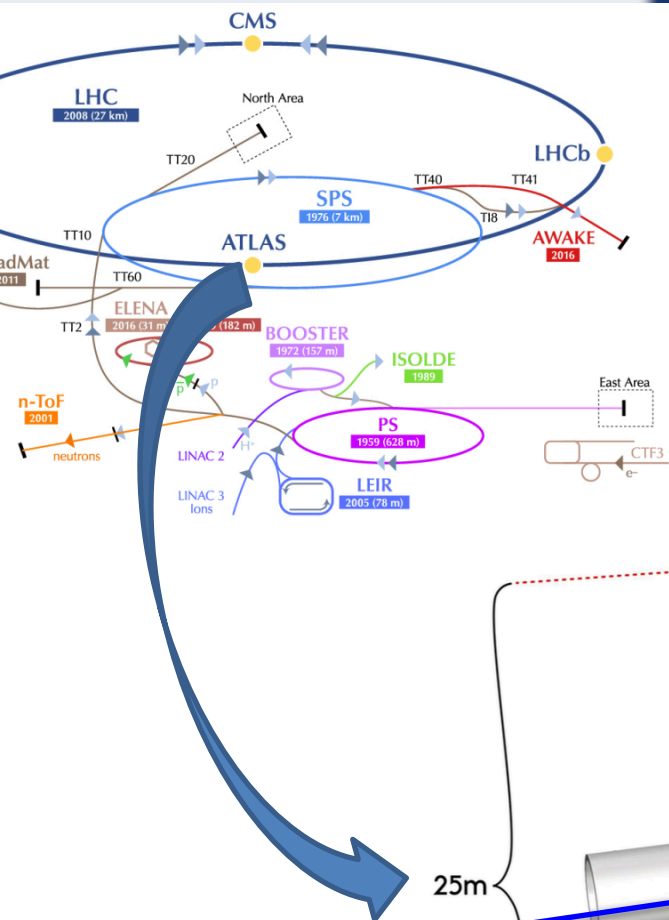
Marcello Bindi,

on behalf of the ATLAS Collaboration

TREDI2020 – 15th Trento Workshop on Advanced Silicon Radiation Detectors
17-19 February – TU Wien - Austria

The ATLAS Inner Tracker

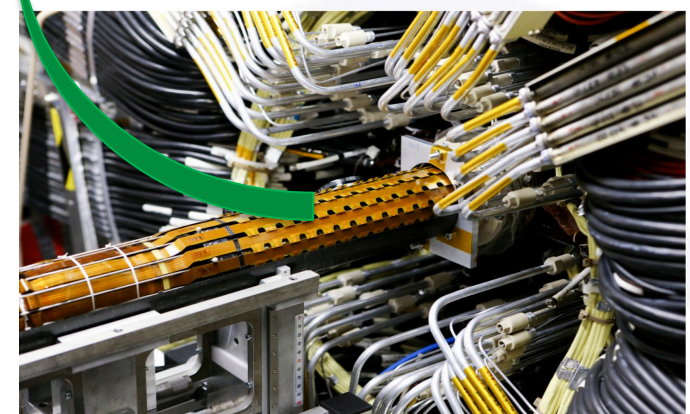
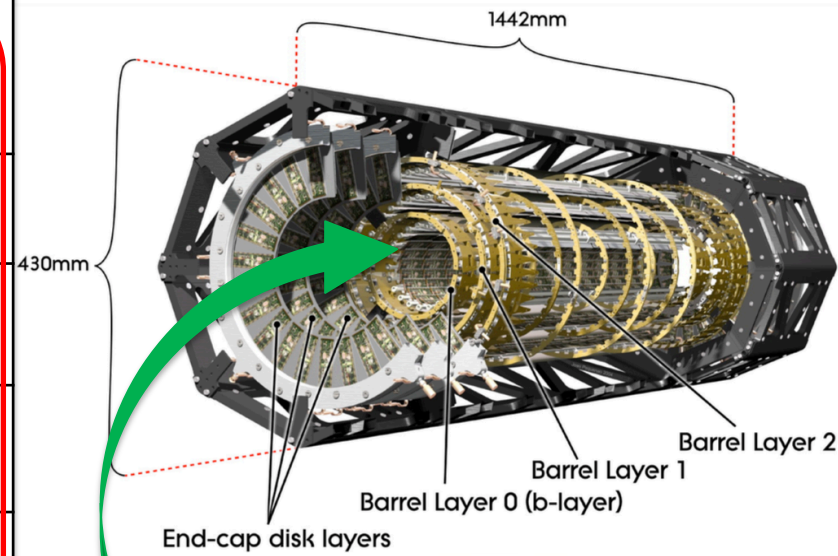
- Pixel Detector
- Silicon Strip Detector (SCT)
- Transition Radiation Tracker (TRT)



The Pixel (+IBL) Detector

3 + 1 barrel pixels layers
3 + 3 pixels endcaps

	Pixel		IBL
Sensor Technology	n^+ -in- n (only planar) 1 mm inactive edge		n^+ -in- n/n^+ -in- p (planar/ <u>3D</u>) <u>~200 μm</u> inactive edge
Sensor Thickness	250 μm		<u>200/230 μm</u>
Front End Technology	FE-I3 250 nm CMOS		FE-I4 130 nm CMOS
Pixel Size	50 x 400 μm^2 (short side along R- ϕ)		50 x 250 μm^2 (short side along R- ϕ)
Radiation Hardness	50 Mrd (500 kGy) $\sim 1 \times 10^{15} \text{ n}_{\text{eq}} \cdot \text{cm}^{-2}$		250 Mrd $\sim 5 \times 10^{15} \text{ n}_{\text{eq}} \cdot \text{cm}^{-2}$
Barrel <Radius> or EndCaps Radius _{Min}	B-Layer	5.05 cm	<u>3.35 cm</u>
	Layer 1	8.85 cm	
	Layer 2	12.25 cm	
	EndCaps	8.88 cm	

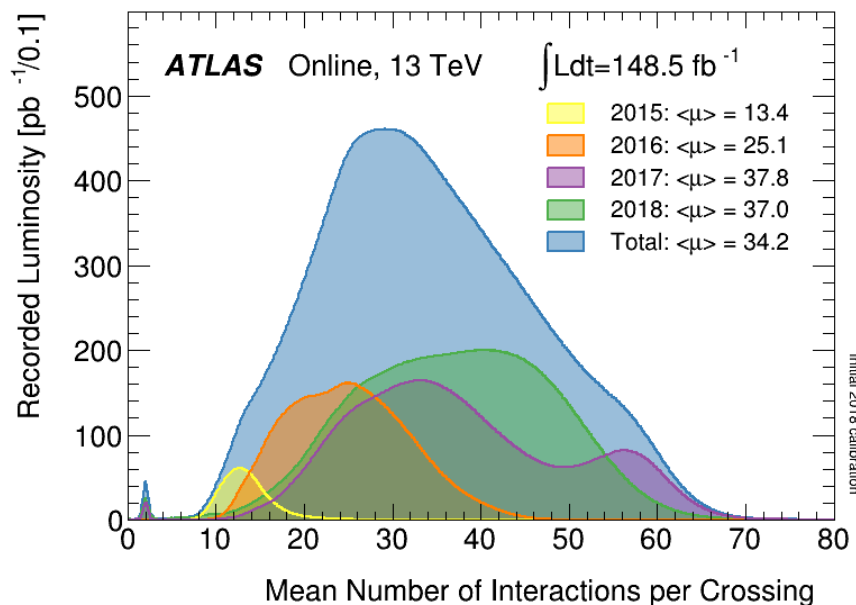
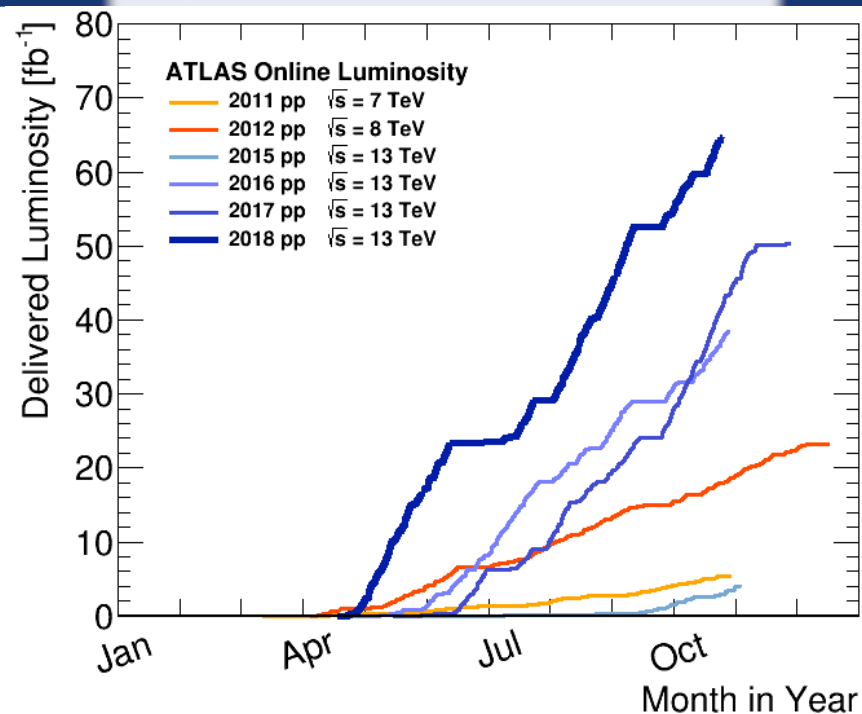


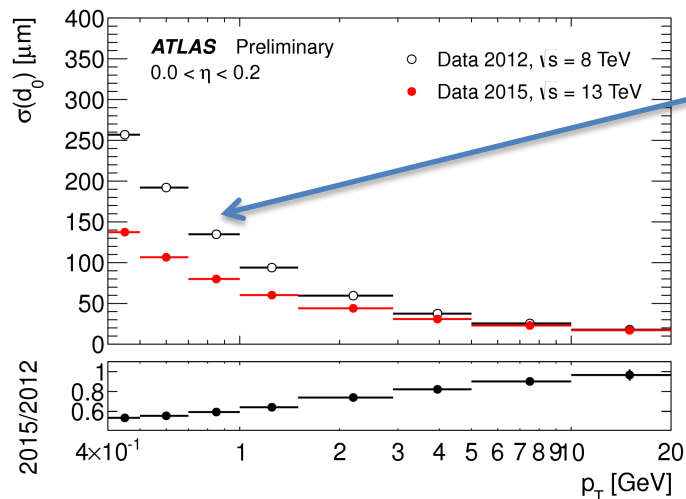
2024 modules, 92 M channels,
1.92 m² of silicon

Insertable B-Layer (IBL)
added in 2014 (Run 2)

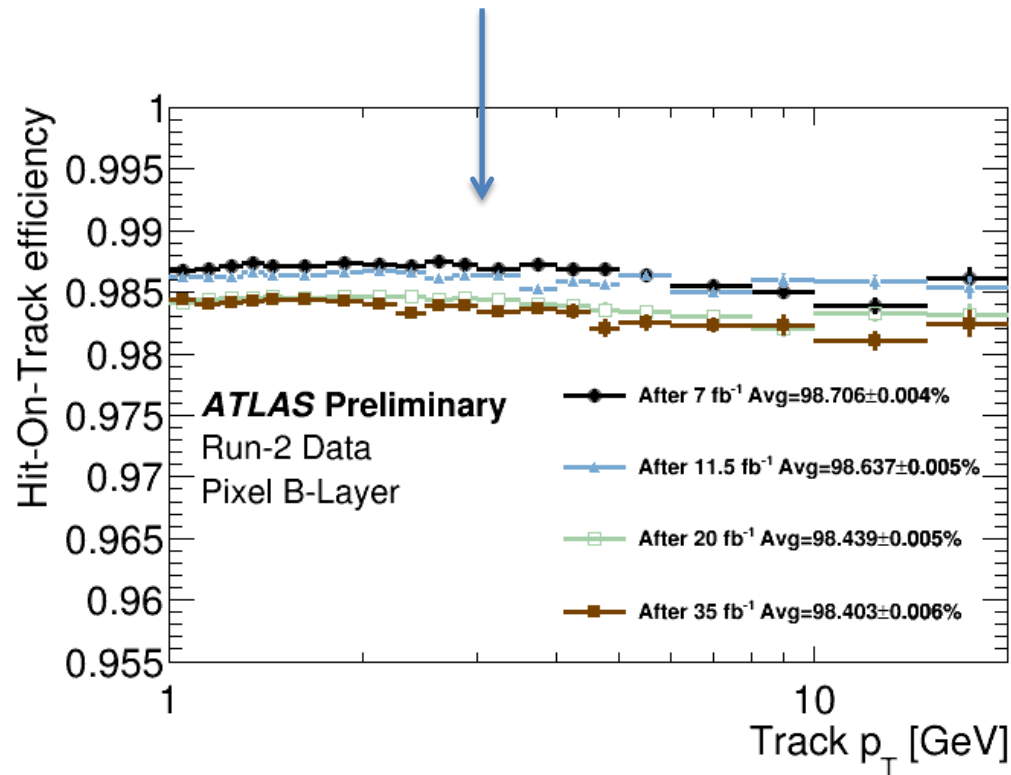
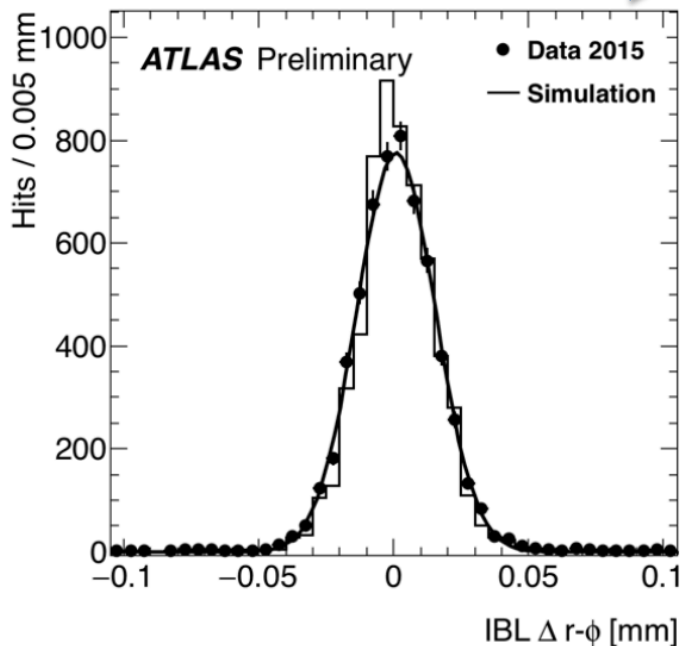
Run 1 vs Run 2 conditions for a typical fill:

- Bunch crossing spacing or **BX** (ns)
 - **BX time** **50 → 25**
- Pile-up or μ (# interactions per BX):
 - **Average** **~20 → ~35**
 - **Peak** **~40 → ~60**
- Instantaneous luminosity ($\text{cm}^2 \text{s}^{-1}$):
 - **Peak** **$\sim 7 \times 10^{33} \rightarrow \sim 2 \times 10^{34}$**
- Integrated luminosity (pb^{-1}):
 - **Average** **~150 → ~500**
- Level 1 trigger rate (kHz):
 - **L1A Rate** **~70 → ~100**



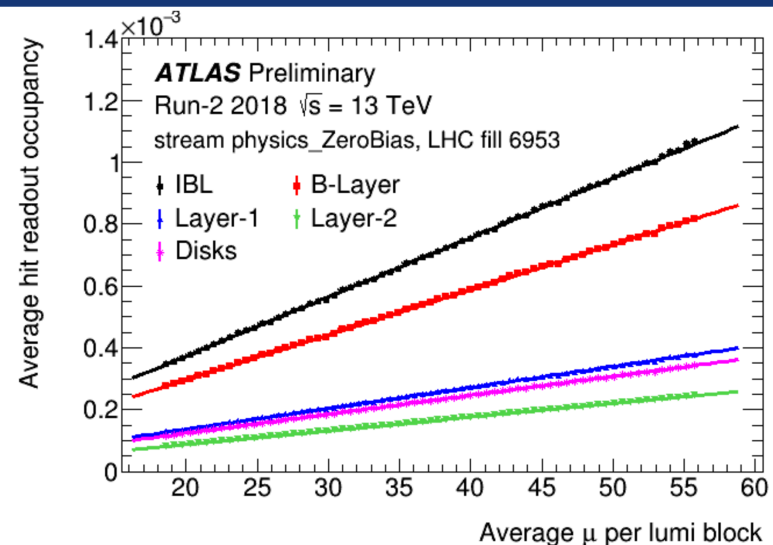


- Impact parameter resolution improvements after IBL insertion (2015)
- IBL spatial resolution $\sim 10 \mu\text{m}$ for the transverse R- ϕ plane (2015)
- B-Layer Hit-on-track efficiency $> 98\%$ (2016)



OCCUPANCY vs PILE-UP

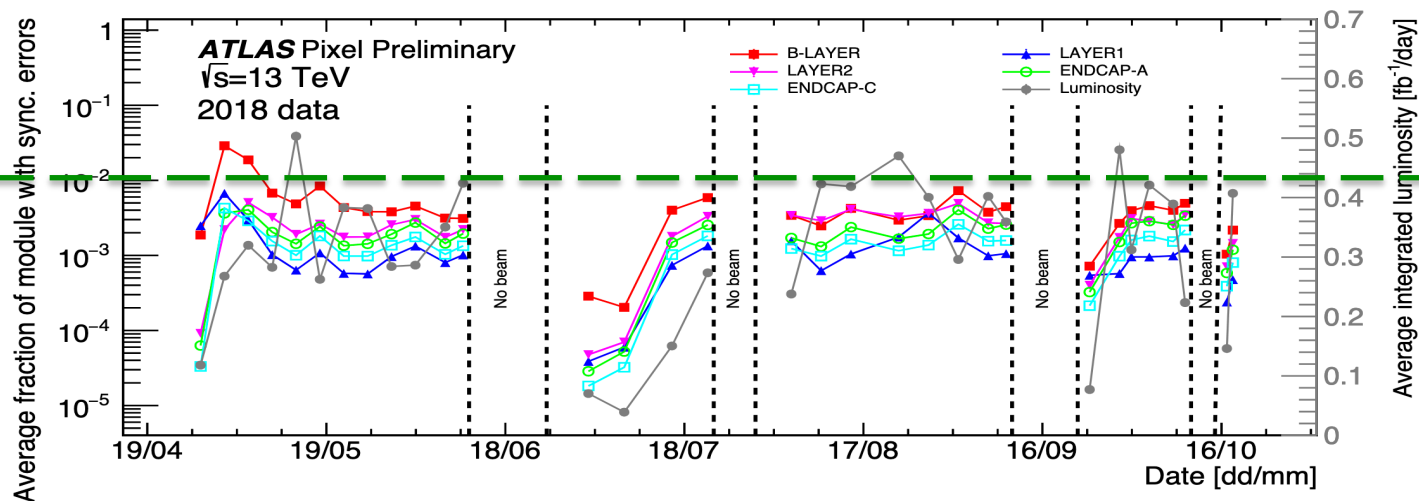
- Occupancy (hit/pixel/event) scales with pile-up
 - several challenges due to **big event size** joint to an **high trigger rate!**
 - high link bandwidth usage $\leftarrow \sim 70\%$



DESYNCRONIZATION

- Desynchronization (event id. mismatch between Pixel modules and ATLAS) **within 1%** despite the increased luminosity along the years.

1%



DEADTIME

- Busy time in ATLAS further reduced in 2018 following previous year trends

Pixel and IBL dead time routinely $\leftarrow \sim 0.2\%$

	Pixel			IBL		
	Integrated Luminosity (fb ⁻¹)	Fluence B-Layer (n _{eq} ·cm ⁻²)	Dose B-Layer (Mrd)	Integrated Luminosity (fb ⁻¹)	Fluence @ Z=0 (n _{eq} ·cm ⁻²)	Dose @ Z=32 cm (Mrd)
Run 1	~30	< 10 ¹⁴	~5	-	-	-
Run 1 + Run 2	~190	<u>~5·10¹⁴</u>	~28*	~160	<u>~1.1·10¹⁵</u>	~53
End of Run 3 (2024?)	~450**	> 10¹⁵	>~ 50 Mrd	~420**	<~3·10¹⁵	~140

* Assuming the same Energy (13 TeV) in Run 1, Run 2, Run 3.

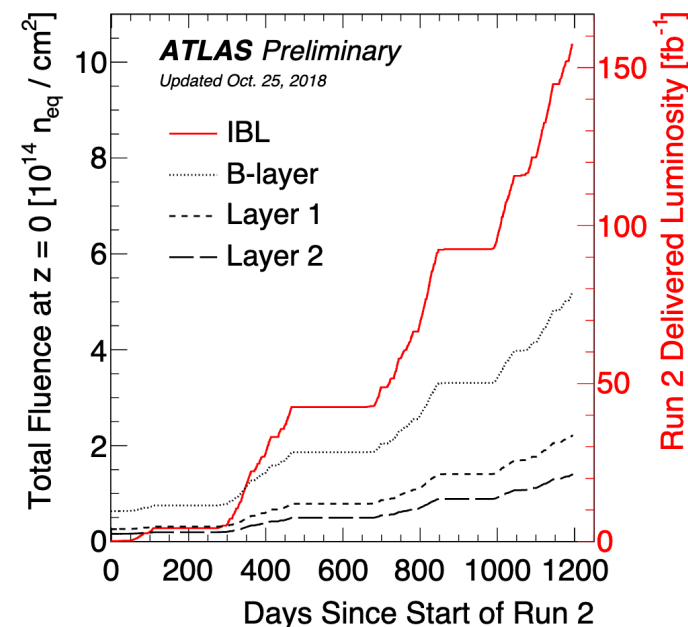
** Assuming an integrated lumi of **260 fb⁻¹** delivered in Run 3.

Calculated using Pythia/Fluka to end of Run 3:

- IBL within specifications (5·10¹⁵ n_{eq}·cm⁻² / 250 Mrd)
- B-Layer above specifications (1·10¹⁵ n_{eq}·cm⁻² / 50 Mrd)

→ Full ATLAS tracker will be replaced at HL-LHC!

→ See [Q. Buat](#) and [J. Lange](#) talks later.

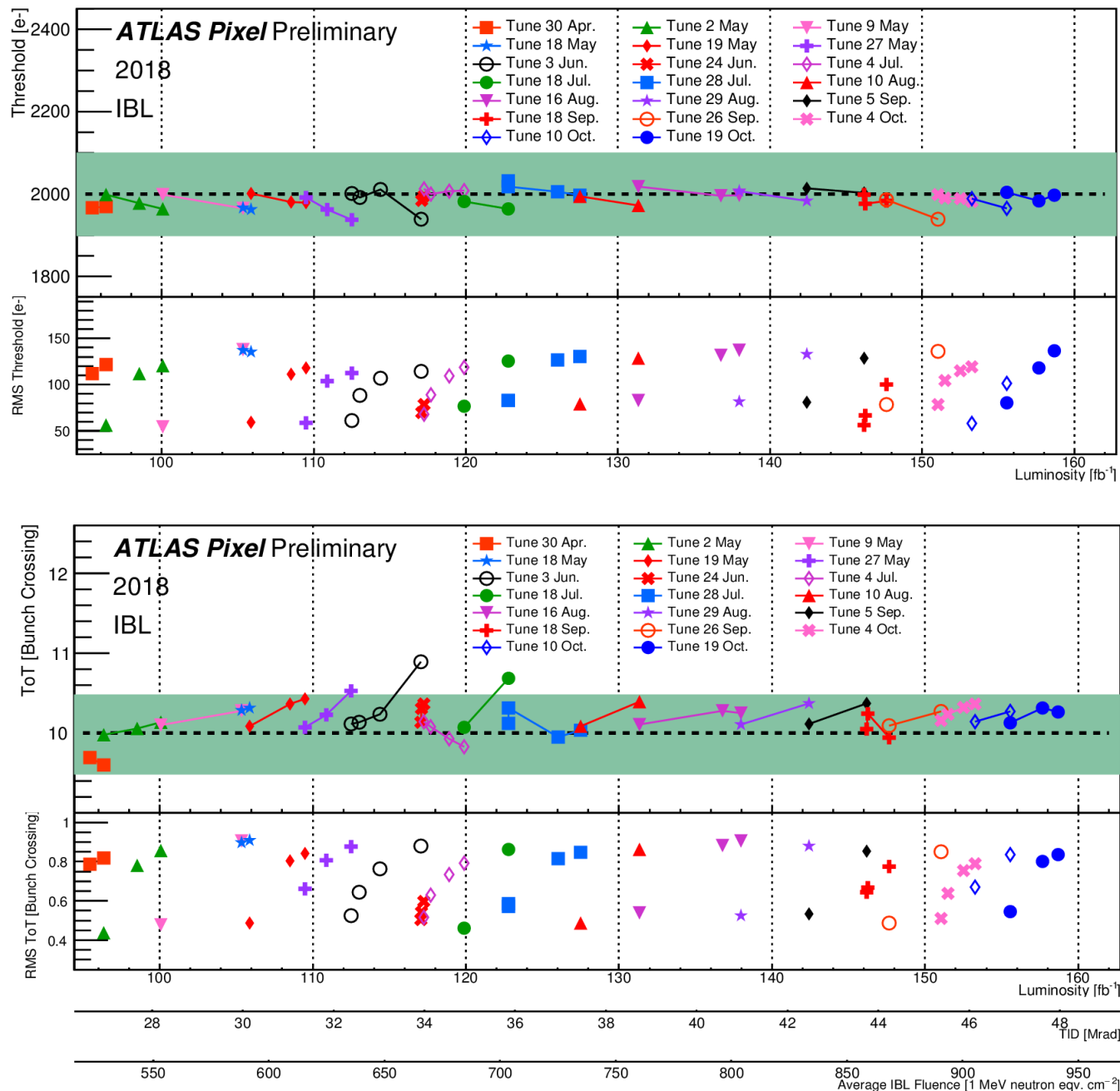


Thresholds

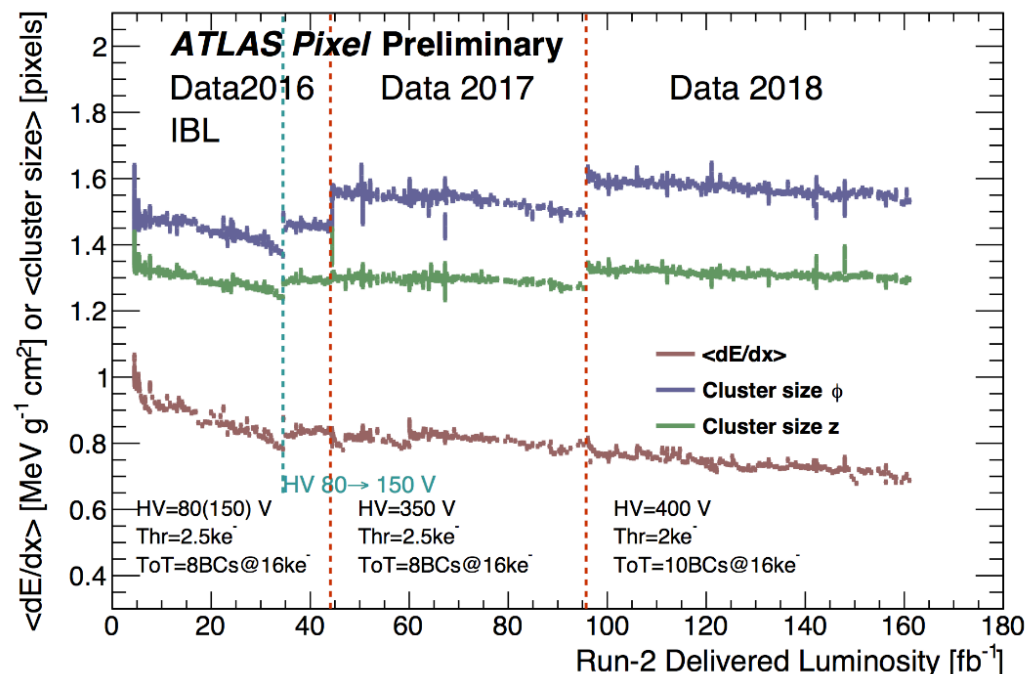
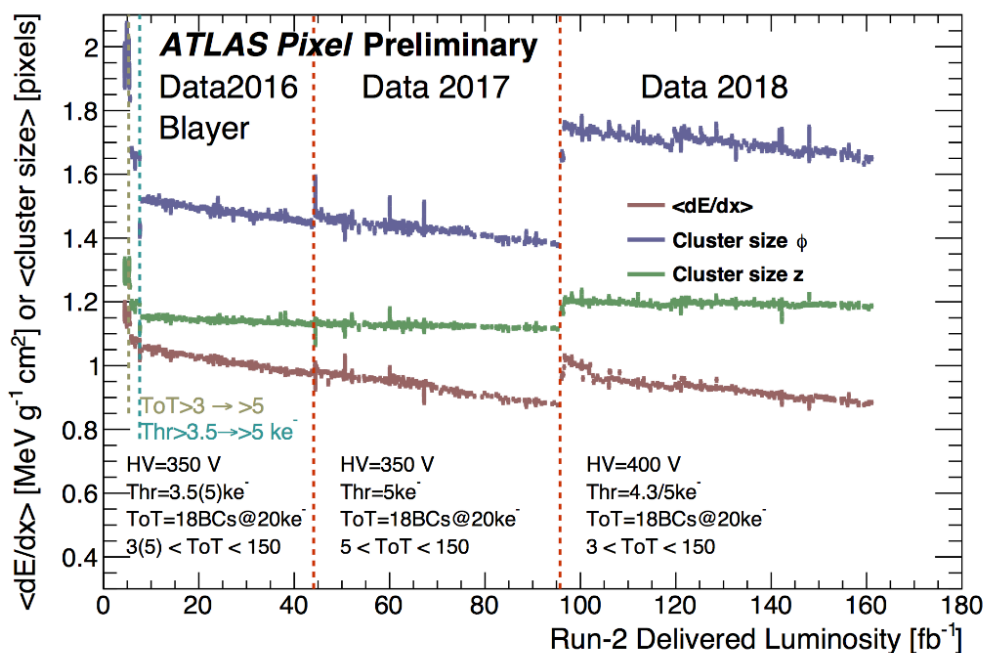
Evolution of FE-I4 parameters in IBL due to known TID effect on transistor leakage currents (130 nm IBM):

→ regular retuning needed!

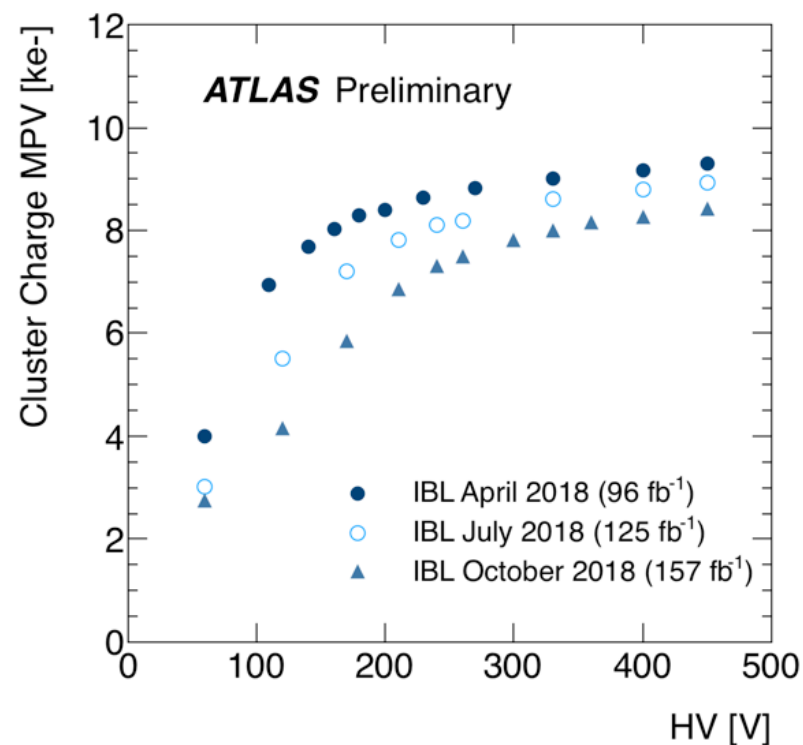
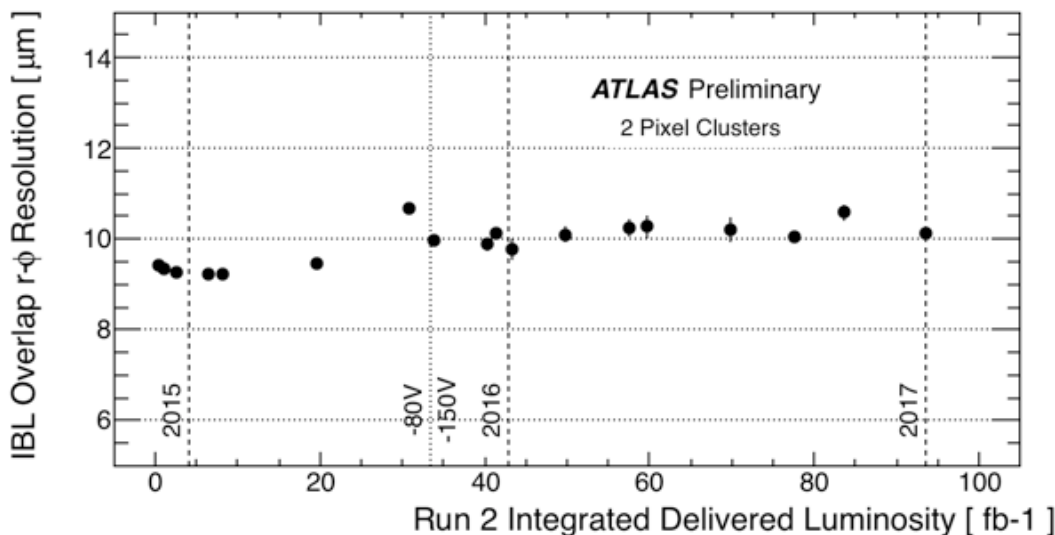
Time over Threshold (ToT)



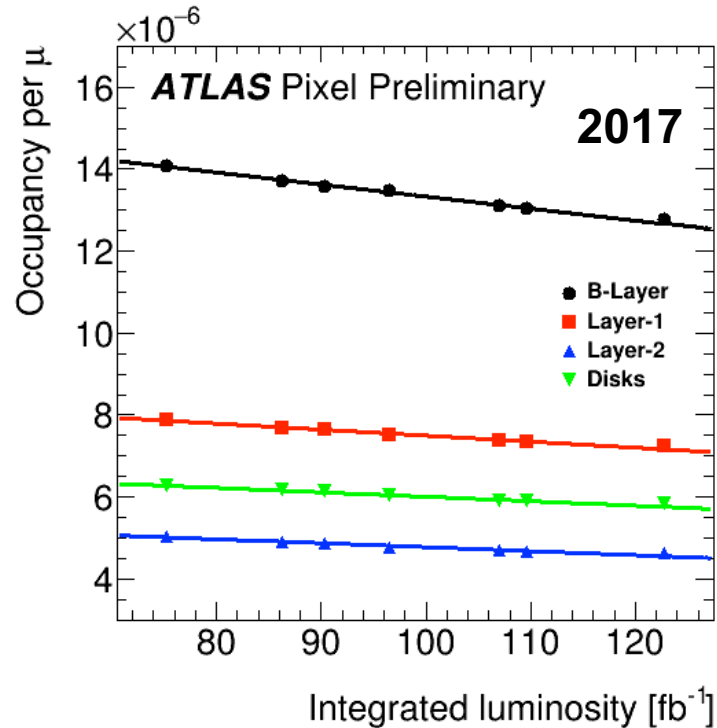
- **dE/dx and cluster size decrease** due to the decreased charge collected (slow slope).
- **HV increased** to assure the detector was fully depleted.
- **Threshold changes** show up (as steps) in dE/dx since hits below threshold do not get recorded
 - ➔ thresholds increased in B-Layer (2016) and Disk (2017) due to limitations on the read-out bandwidth between modules and off-detector electronics.



- **IBL hit spatial resolution quite stable:**
 - used only clusters with two pixels in the overlap region
 - small degradation observed by the end of 2017 ($\sim 95 \text{ pb}^{-1}$).
- Charge collection constantly measured via **bias voltage scans** performed for different integrated luminosity
 - MPV of the fitted Landau distribution of TOT clearly affected
 - **decrease of plateau values associated to shape changes.**



- **Hit occupancy per μ** decreases with integrated luminosity (2017).



➔ **Increase HV** to fully deplete the sensors and **decrease the thresholds** to recover from the loss of charge collection efficiency

RUN-2 HV

HV	2015	2016	2017	2018
IBL	80V	150V	350V	400V
B-layer	250V	350V	350V	400V
Layer-1	150V	200V	200V	250V
Layer-2	150V	150V	150V	250V
Endcap	150V	150V	150V	250V

- However, bandwidth limitations from module to off-detector electronics appear if thresholds too low!

ATLAS Run2 benchmark

L1Trigger = 100 kHz
 $\langle \mu \rangle = 60$

- Different thresholds within the same detector layer (B-Layer) were explored:

5000e (high $|\eta|$ modules)

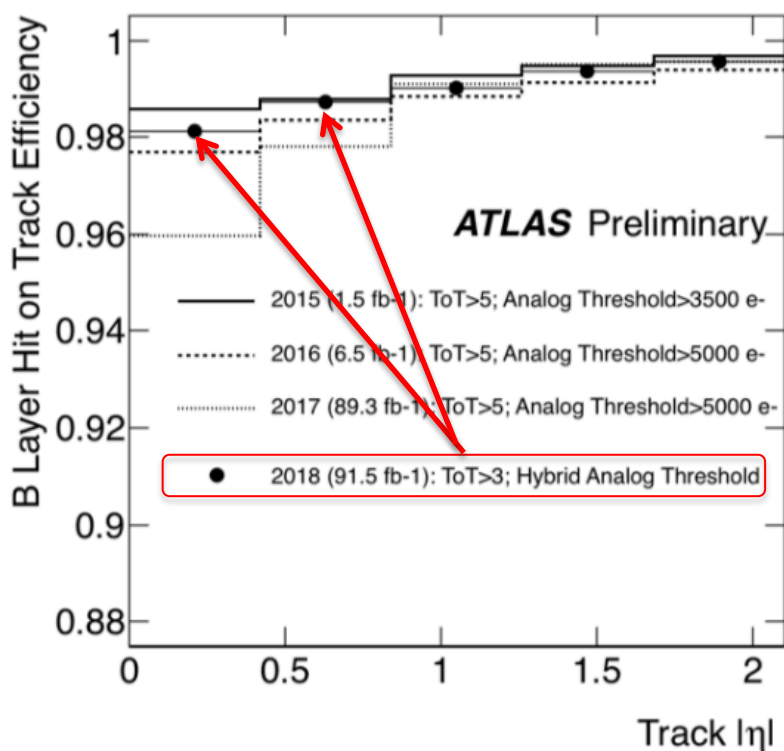
VS

4300e (low $|\eta|$ modules)

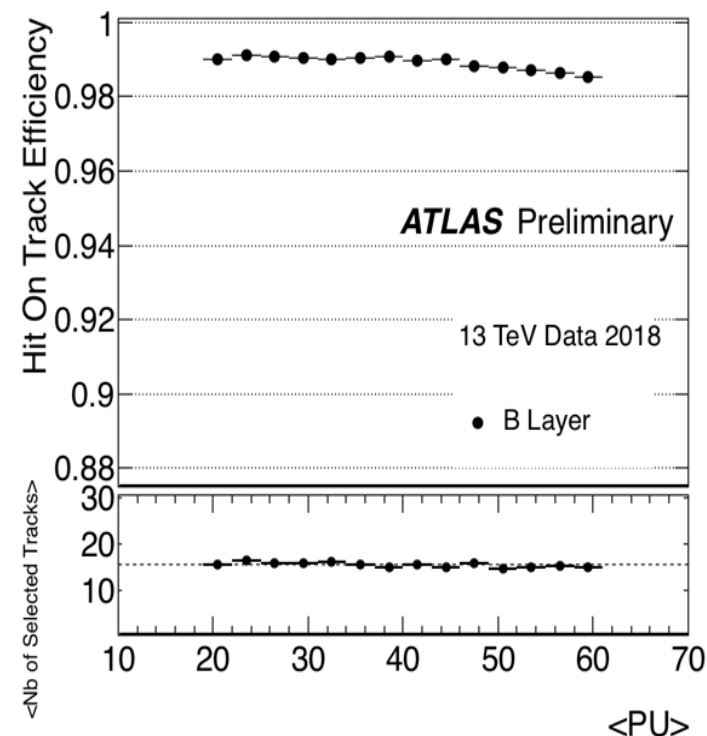
Hybrid analog threshold configuration in B-Layer

- Recovering hit on track efficiency in the central area (more affected by radiation damaged) without increasing too much the occupancy elsewhere.

Recovered the 2015 efficiency!

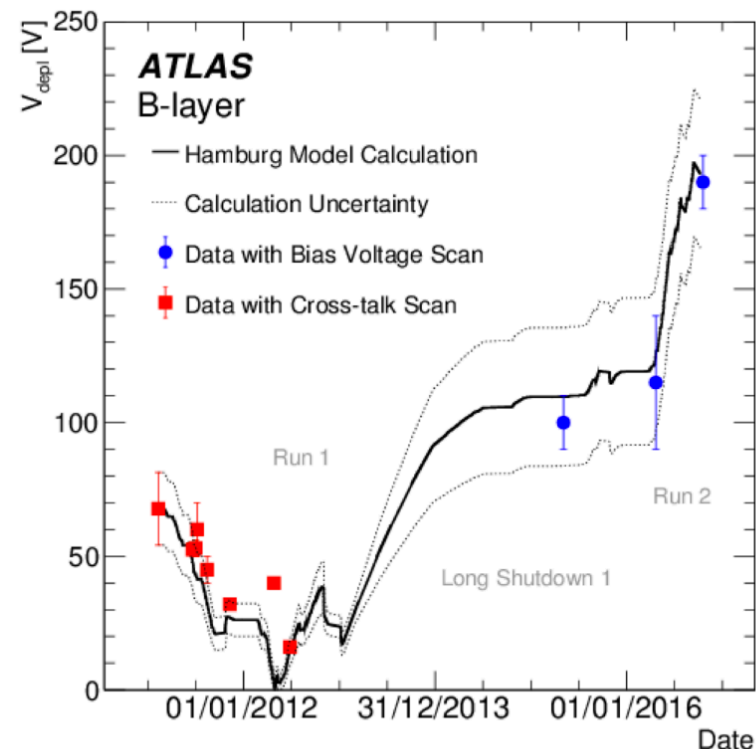
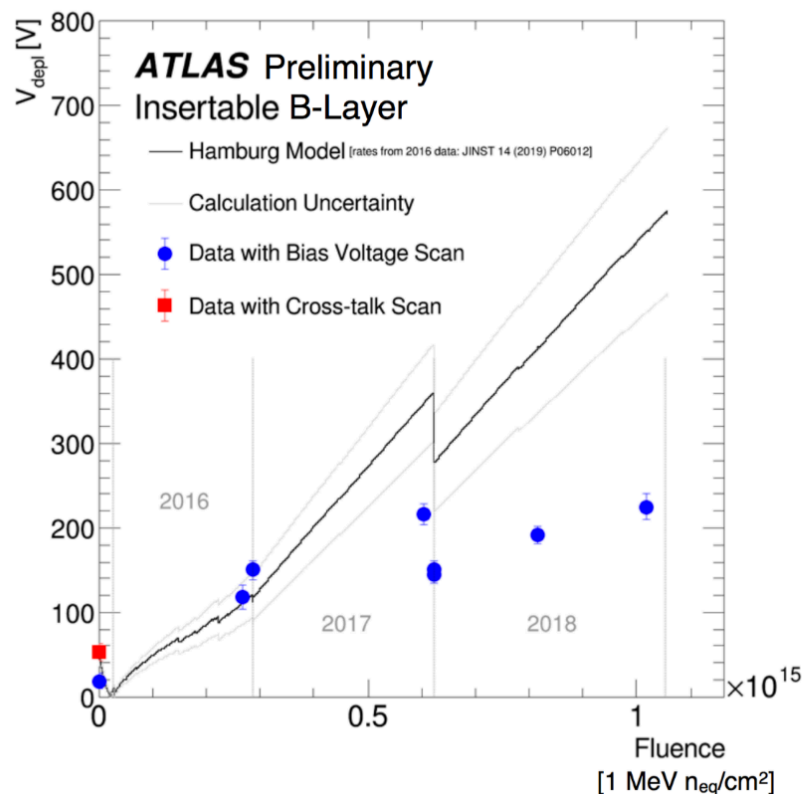


Hit on track efficiency vs μ at ~99%

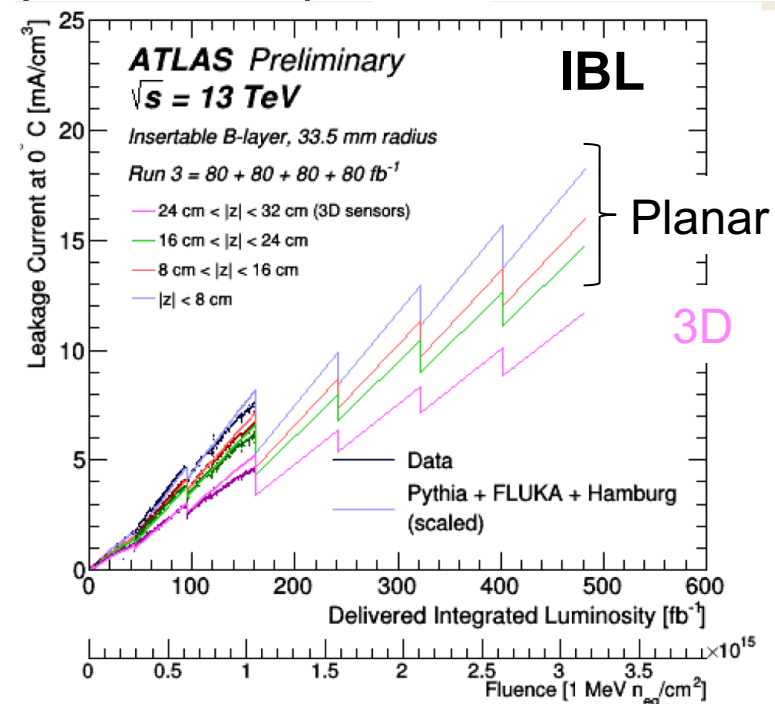
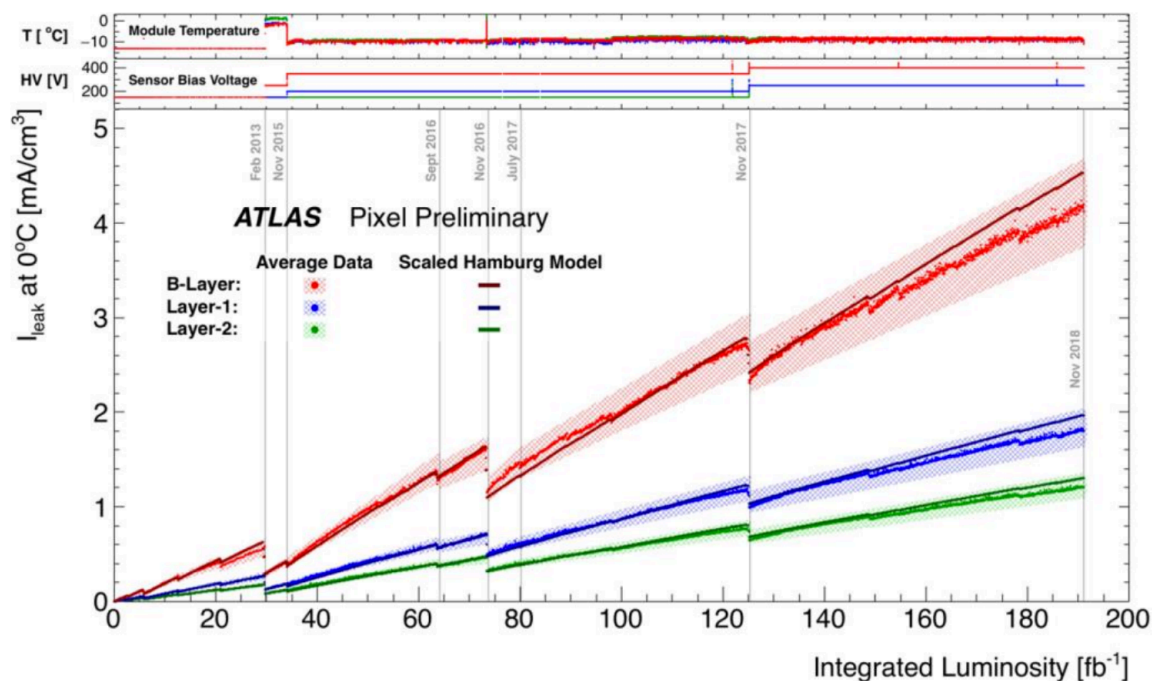


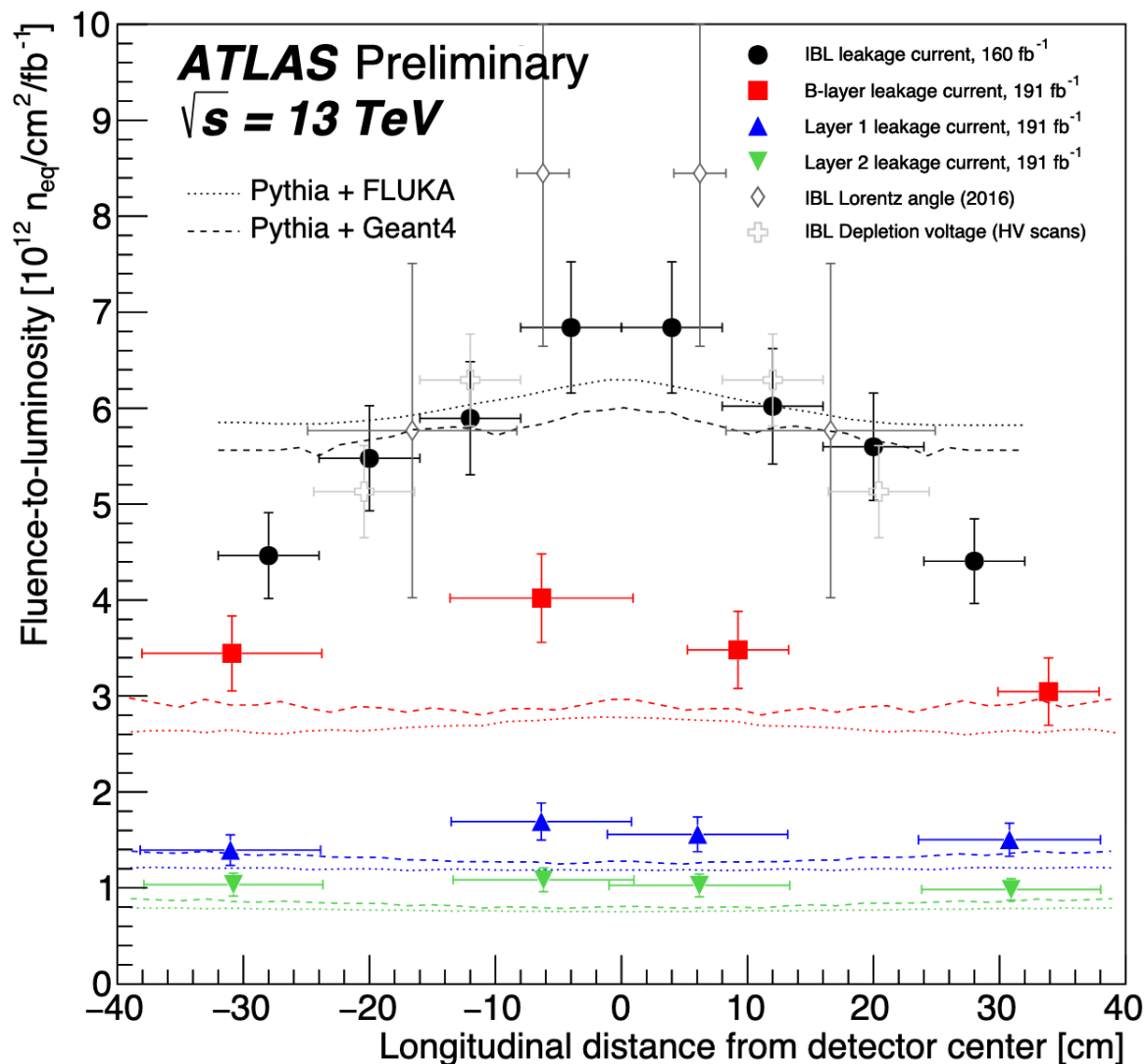
Higher bias voltage needed for full depletion and efficient charge collection:

- Hamburg model predictions vs data from bias voltage scan (or cross talk scan before type inversion)
- Full depletion is well predicted by the Hamburg Model at lower fluences and over predicted at higher fluences.



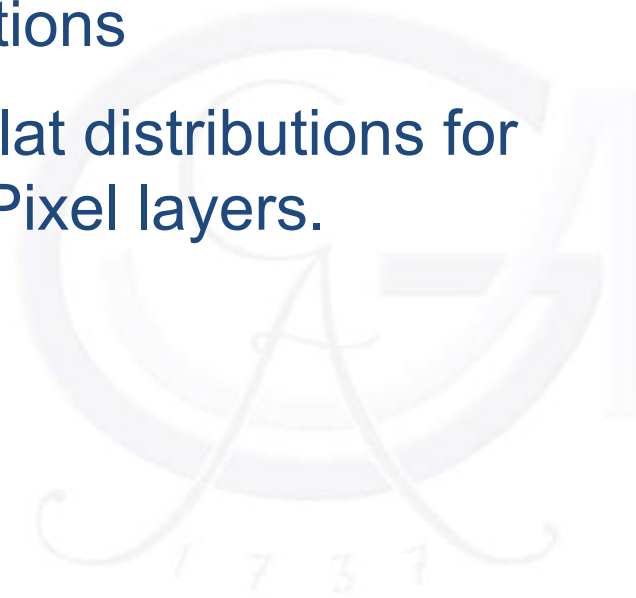
- Measured leakage currents quite well described (annealing, temperature dependence) by the Hamburg Model but:
 - scaling factor per layer and z bin is required
 - towards the end of Run 2, the leakage currents seem overestimated.
- Pixel:** Leakage current per module expected at the end of Run 3 within the power supply limitation (< 2 mA per sensor).
- IBL:** Leakage current per module expected at the end of Run 3 within the power supply limitation (< 5 mA per sensor).



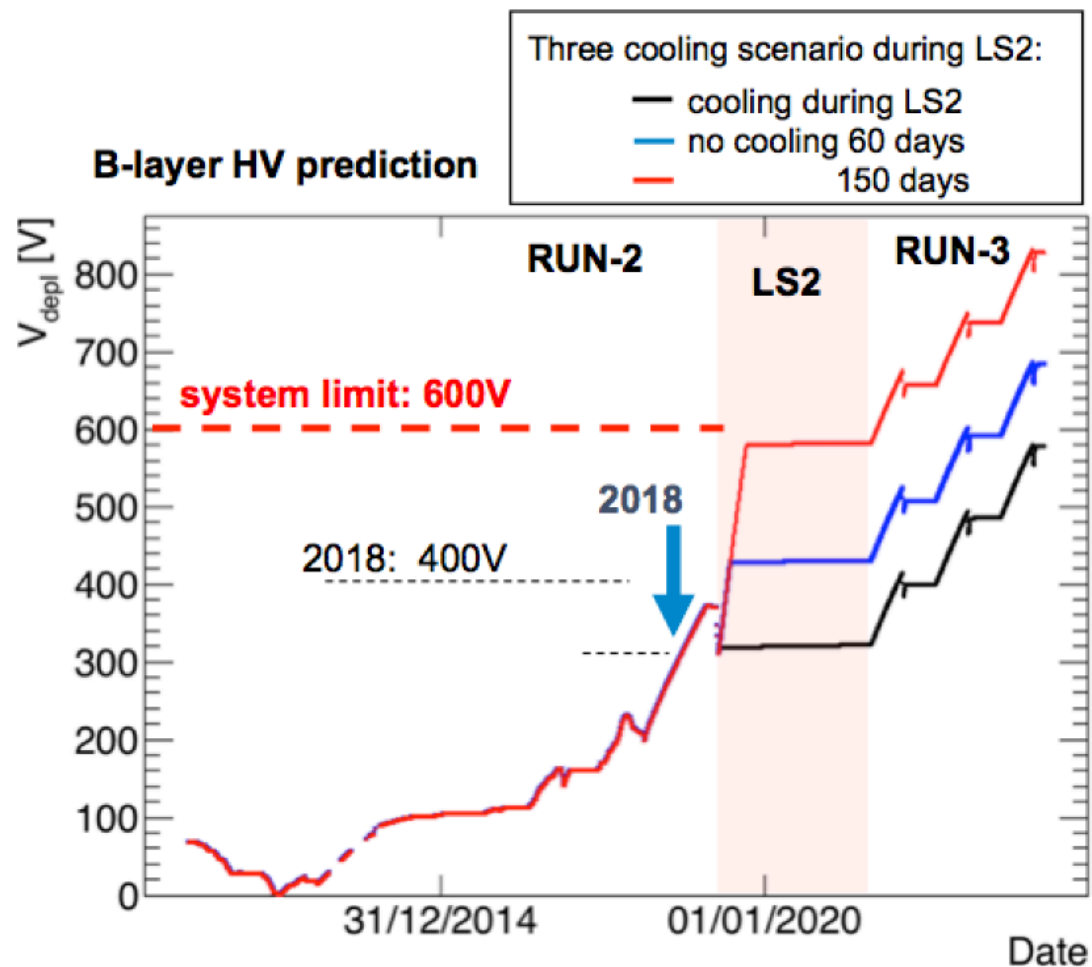


Fluence-to-luminosity conversion factors extracted from the leakage current, Lorentz angle and Depletion Voltage measurements:

- **less fluence at high $|z|$ on IBL data** respect to Pythia + FLUKA/Geant4 predictions
- more flat distributions for outer Pixel layers.



- **Keeping the detector cold during LS2 to prevent reverse annealing**
→ keep the depletion voltage under control (B-layer, IBL).
- Warm up periods unavoidable due to the ID maintenance during LS2
- Target to stay **warm for < 60 days** during the LS2.
- Detector warm for **17 days up to now**.
- Expecting about 2 more weeks
→ **total of 31 days**.
- Exploring colder operating set points in these days ($-25^{\circ}\text{C}/-30^{\circ}\text{C}$).



Temp set point during LS2	PIXEL	IBL
Detector Unpowered	-5°C	-5°C
Detector Powered (Cosmics)	-20°C	-20°C

- New Pixel digitization model was developed and is now under validation before entering the official ATLAS simulation

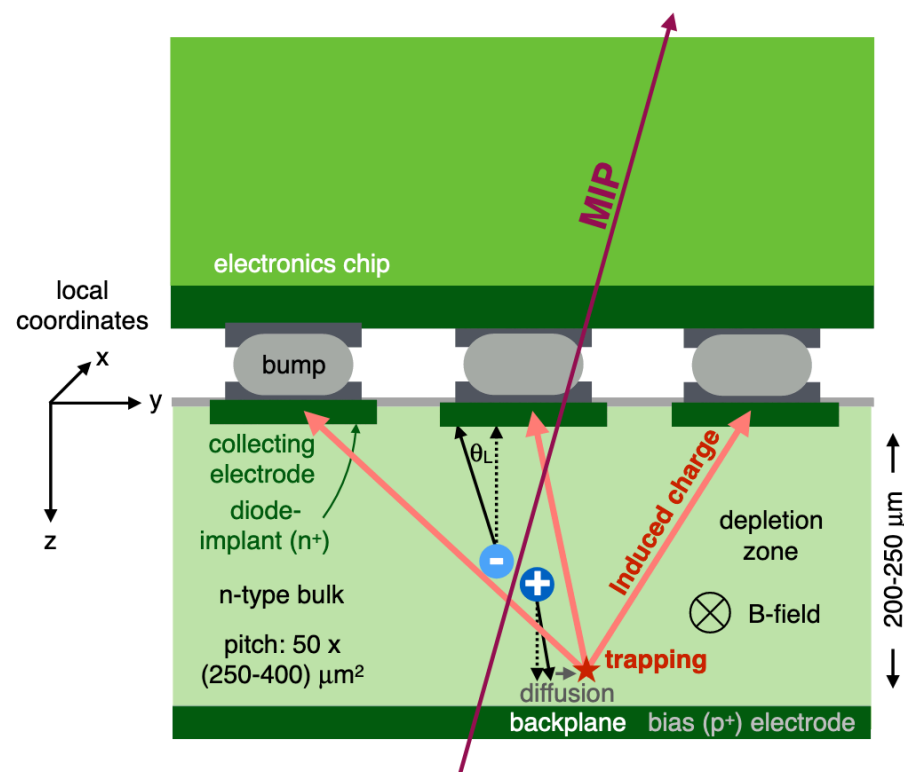
Recent paper available here: [JINST 14 \(2019\) 06 P06012](#)

- Charge carriers will drift toward the collecting electrode due to **electric field**, which is deformed by **radiation damage (double peak)**.
- Their path will be deflected by magnetic field (Lorentz angle) and diffusion.
- Electron and hole lifetime inversely proportional to fluence:

→ **charge trapping,**

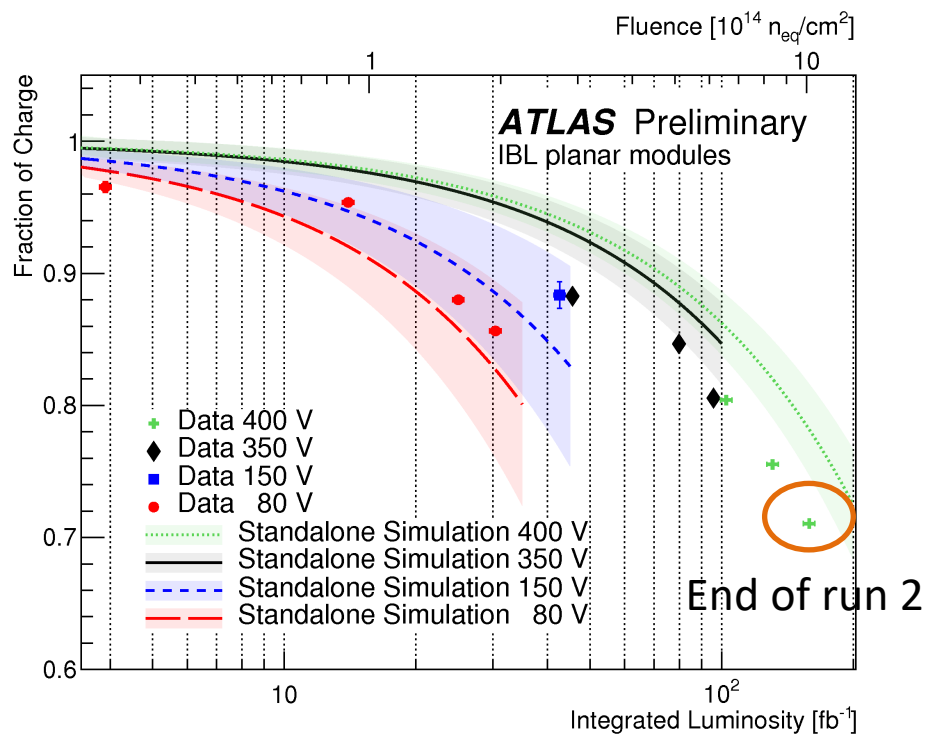
→ reduction of the collected charge.

- Available for both **Planar** and **3D** sensors.



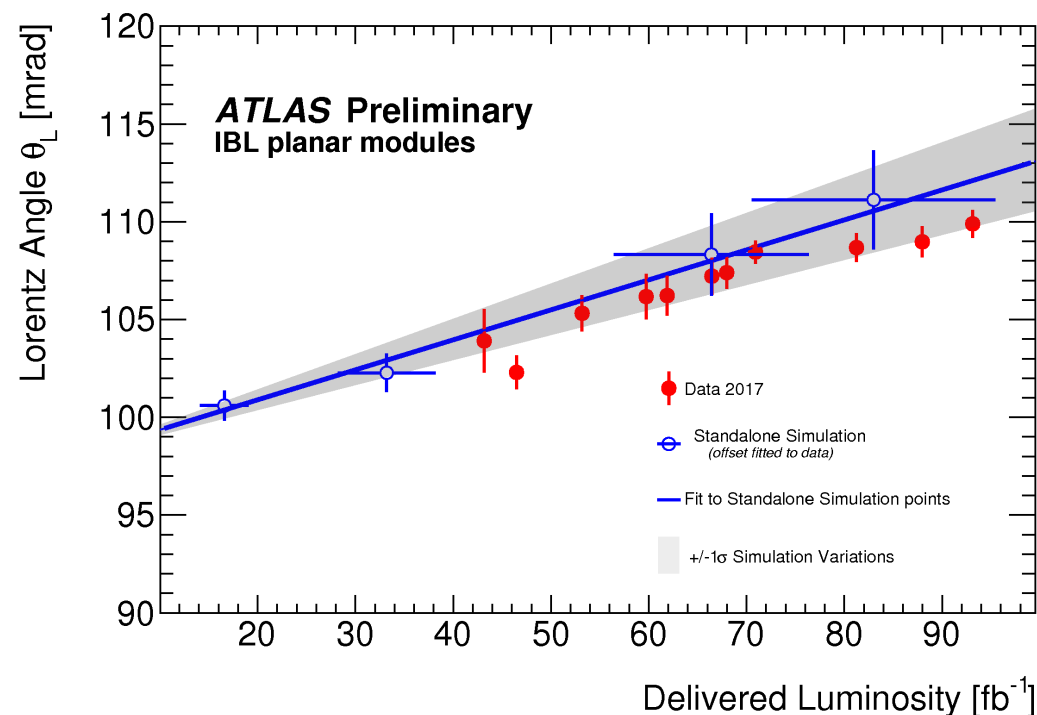
Charge Collection Efficiency (CCE) for IBL modules with $|\eta| < 0.2$ at the end of Run 2 is **~70%**

- MPV at the end of Run 2 **~10 ke**, with a front-end threshold of **2 ke**.



Lorentz Angle extracted from a fit to the cluster size vs track incident angle:

- big variations when bias voltage or temperature change
 - further changes due to changing electric field shape inside the sensor
- ➔ probing the electric field profile.



SEE: big charge deposit in FE electronics can flip the state of a global or local memory cell.

- IBL FEs started being affected by SEE in 2017 → **periodical reconfiguration of FE global registers.**

• However, increase of :

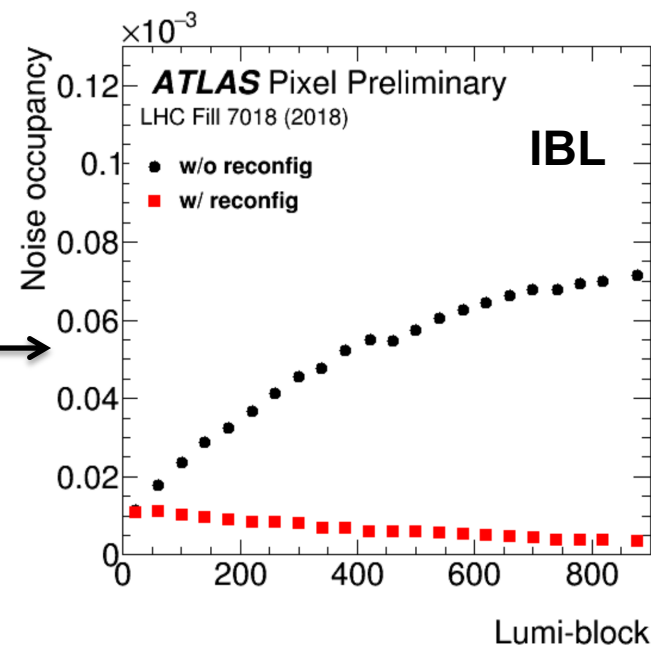
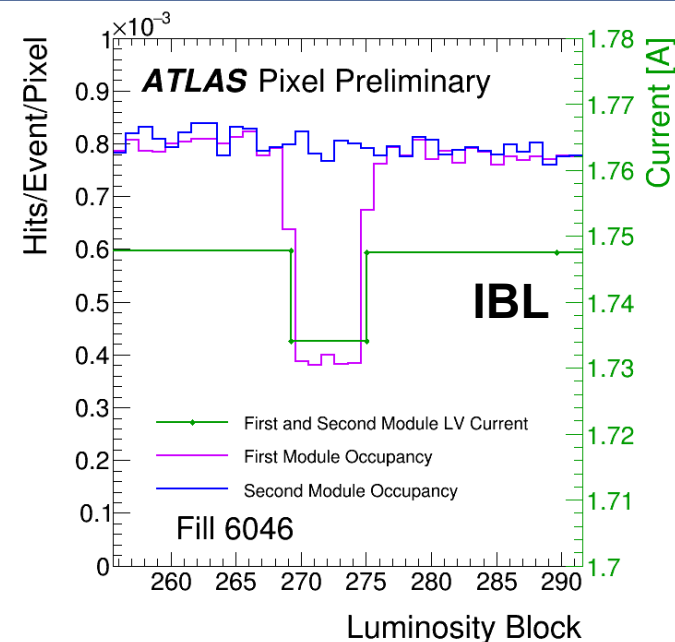
- **noisy pixels** (pixels firing in the empty bunches)
- **quiet pixel** (pixels not firing in colliding bunches)

due to **SEE in single pixel latches** that modify:

- **local threshold DAC (TDAC)**
- **return to baseline DAC (FDAC)**
- **enable bit.**

- Solved by a periodical reconfiguration of the **FE global register + single pixel latches** → clear gain from reconfiguration in test run in 2018.

- The fully FE reconfiguration every few minutes will be the **default approach in Run 3!**

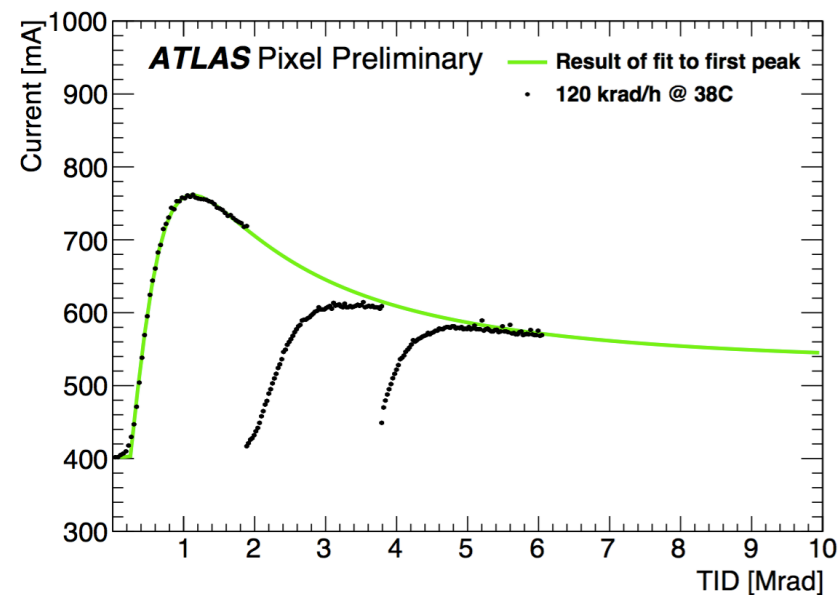
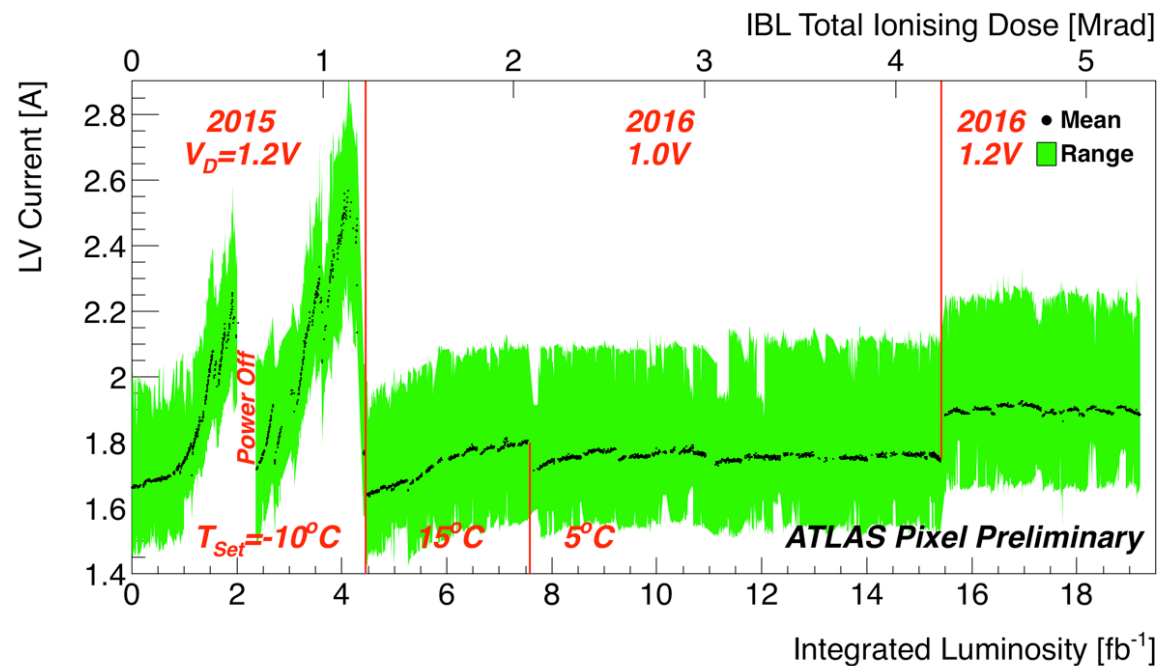


- Several operational challenges/adjustments since beginning of Run 2:
 - **lowered thresholds** for **IBL**, **B-Layer** and **Disk**
 - **increased bias voltage** for **all the layers**.
 - ➔ time for **consolidation, automatization and optimizations!**
- Pixel/IBL **dead time** reached **minimal** values ($\sim 0.2\%$), with an **excellent data quality** (99.5%) despite the high pile-up/luminosity.
- Reliable and efficient operation of **planar sensors** (small inactive edge) at full depletion voltage (400 V).
- Novel **3D technology** used successfully for the first time in HEP, operating at **lower HV** (40 V).
- Fundamental to **understand and forecast the effects of radiation**:
 - **validate the new digitization model** available for the **MC**
 - **mitigate the radiation damage** (V_{th} , HV, Cooling)
 - **keep the detector cold** (-5°C)
 - **decrease the operating temperature** ($< -20^{\circ}\text{C}$)
 - **enhance the FE reconfiguration** operation to limit the impact of SEE.

Back-up

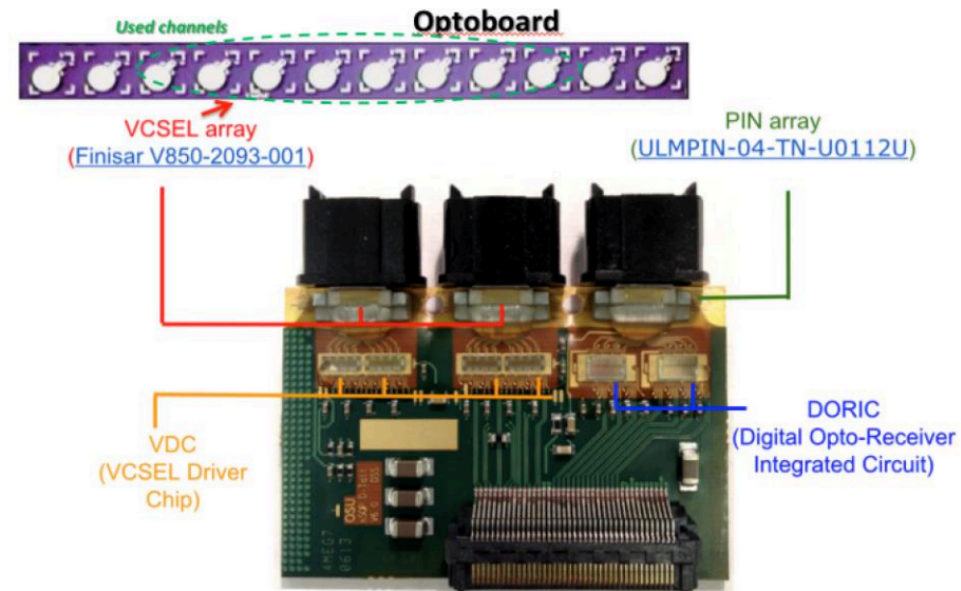


- IBL Total Ionizing Dose (TID) effect causing relevant increase of FE currents

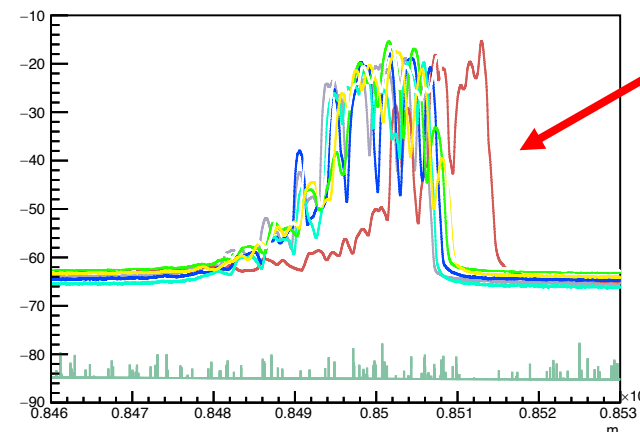


["Production and Integration of the ATLAS Insertable B-Layer"](#)
JINST paper for more info about IBL

- **High failure rate of VCSELs** since start of Run 2 (on-detector data transmission).
- Cause of the failures not fully understood:
 - **humidity**
 - thermal cycling of VCSELs due to non-DC-balanced transmission.
- About **30 boards** were already **replaced** before the start of 2018 run
 - **20 new VCSELs** died in 2018/2019
→ 20 modules not operational.
- Failed (or suspected to fail) optoboards will be **replaced next summer**
 - better sealing planned to decrease humidity.

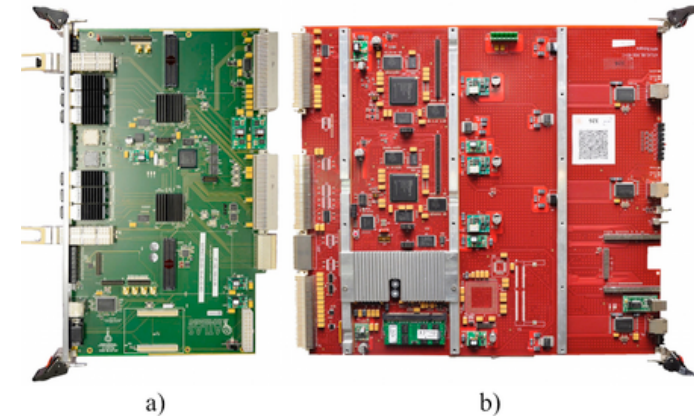


Possible to predict the failure



Shifted spectra of the single VCSEL respect to the rest of the channels in the array.

- The Run 1 Pixel read-out system went through a series of upgrades using the new IBL read-out:
 - Layer2 (2015/2016 Winter Shutdown)
 - Layer1 (2016/2017 Winter Shutdown)
 - B-Layer/Disks (2017/2018 Winter Shutdown)



- Overcome bandwidth limitations but also enhance debugging capability and Sw/Fw flexibility.
- Finally in 2018, one unified read-out system that should bring Pixel many advantages on a longer term:
 - the operation of different type of FEs will always be there but...transparent for most of the operations!

Expectations for 2017 were:

Limitations to be expected in module to read-out system bandwidth

➔ Pixel high lumi task force recommended an occupancy reduction in Disk.

Hit occupancy in disks was reduced by ~20% to maintain sustainable operation:

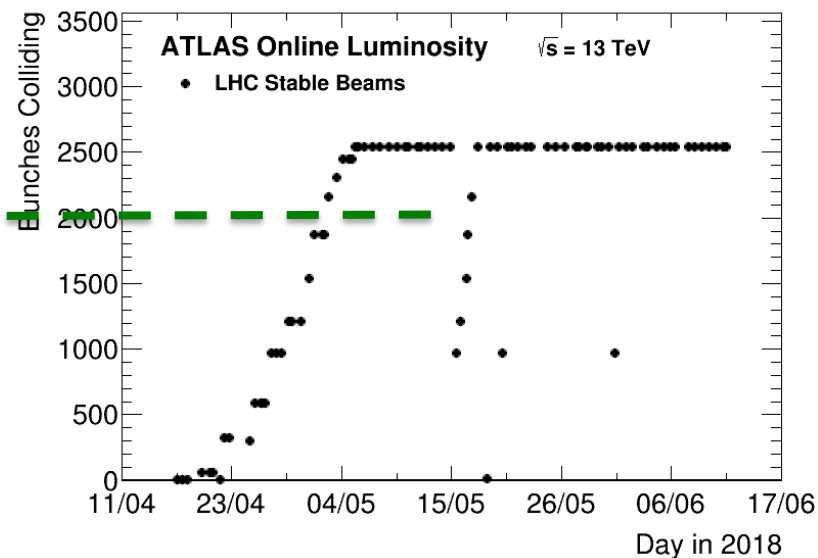
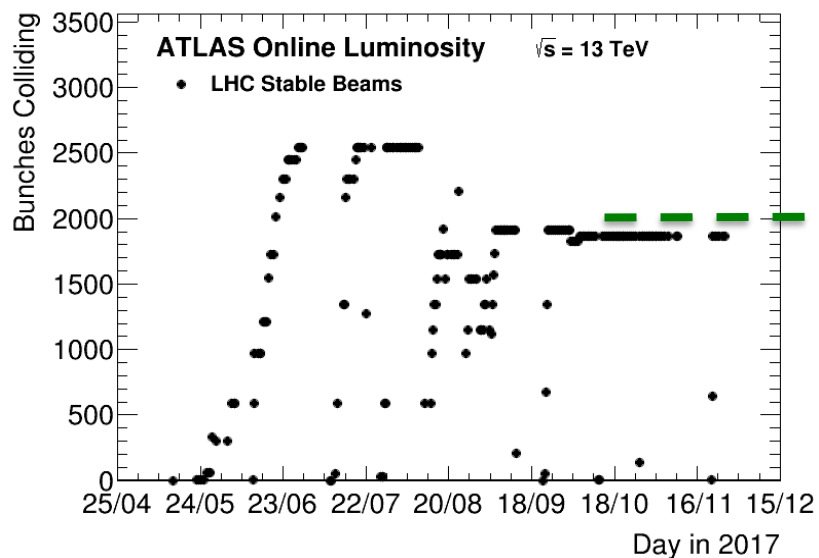
- increase analog threshold: 3500 e⁻ → 4500 e⁻
- increase digital threshold : 5 (TOT) → 8 (TOT)

Layer	Analog Threshold [e ⁻]	Digital ToT cut [BC]	Latency [BC]	Tuning
B-layer	5000	5	150	ToT = 18 @ 20,000 e ⁻
Layer 1	3500	5	255	ToT = 30 @ 20,000 e ⁻
Layer 2	3500	5	255	ToT = 30 @ 20,000 e ⁻
Disks	4500	8	255	ToT = 30 @ 20,000 e ⁻
IBL	2500	n/a	255	ToT = 8 @ 16,000 e ⁻

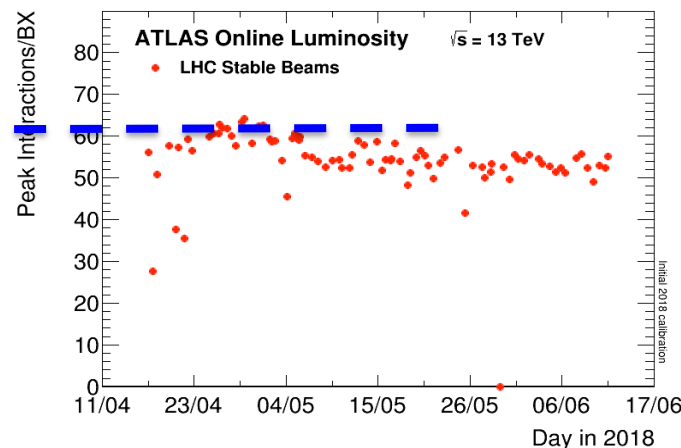
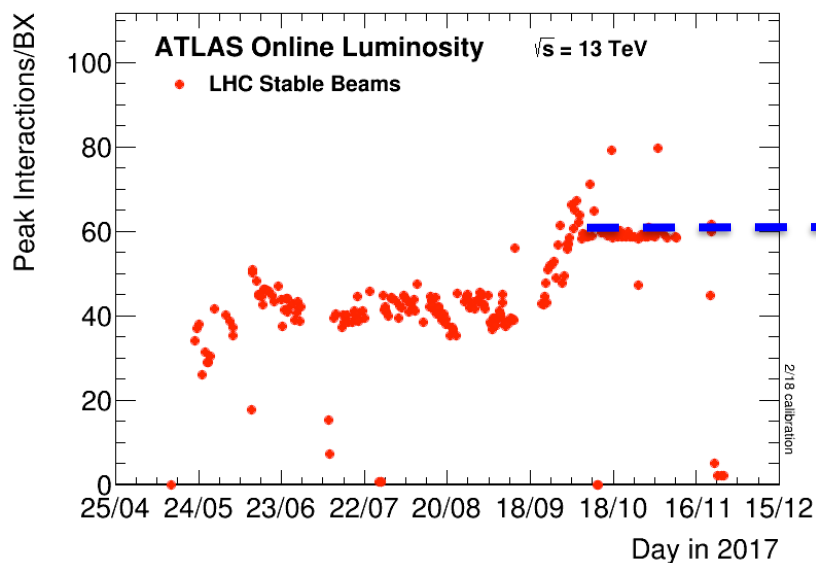
Frist clear effects of the radiation damage:

- after accumulating ~ 45 fb⁻¹, a decrease of charge collection efficiency (trapping) was observed:
➔ plan to increase HV in 2018 and possibly reduce the thresholds if bandwidth allows!

- More colliding bunches in the ring.....from ~2000 to 2544



- Pile-up always below 60 due to bunch intensity limitations



Threshold	2017	2018
IBL	2500e, ToT>0	2000e, ToT>0
B-layer	5000e, ToT>5	4300e(*), ToT>3
Layer-1	3500e, ToT>5	3500e, ToT>5
Layer-2	3500e, ToT>5	3500e, ToT>5
Endcap	4500e, ToT>5	3500e, ToT>5

* central Eta: 4300e high Eta: 5000e

Keep adjusting threshold and HV but...

limitations on the read-out bandwidth if thresholds decreased too much!

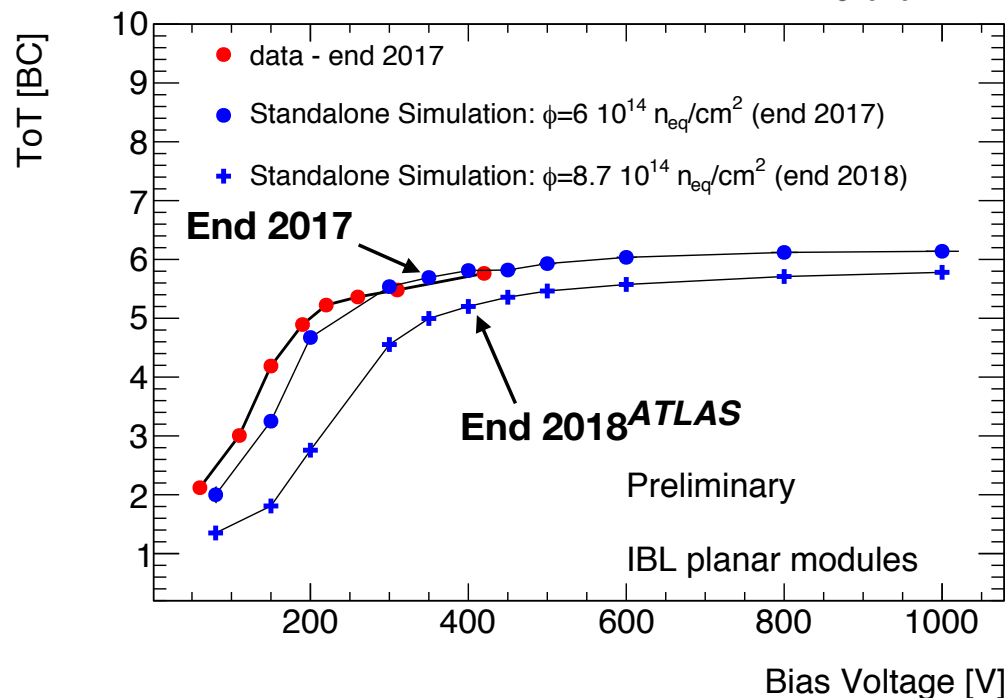
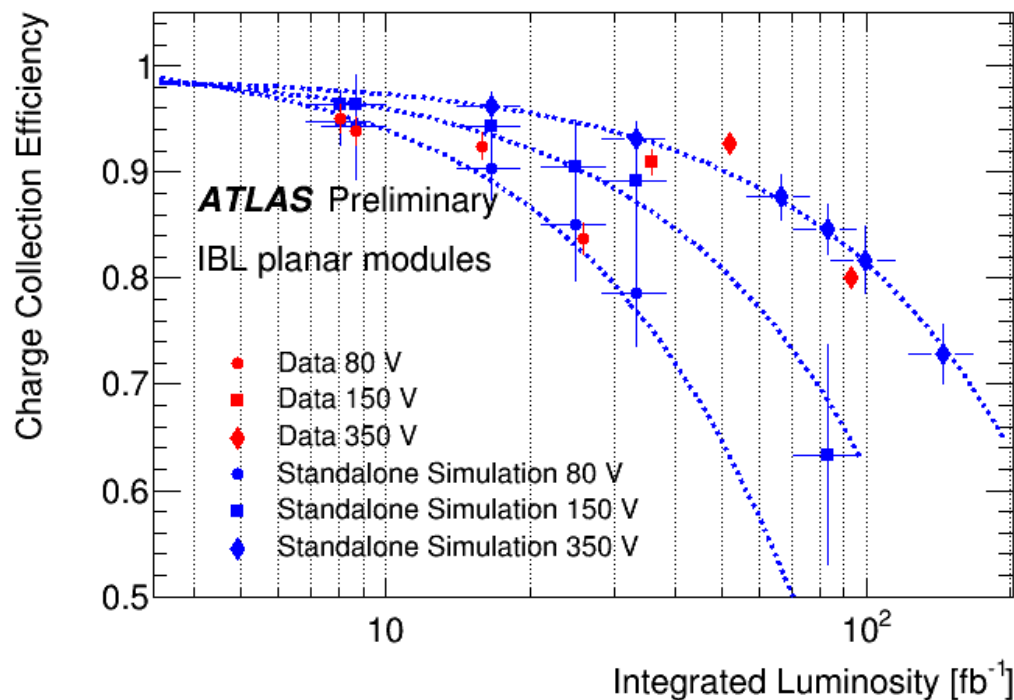
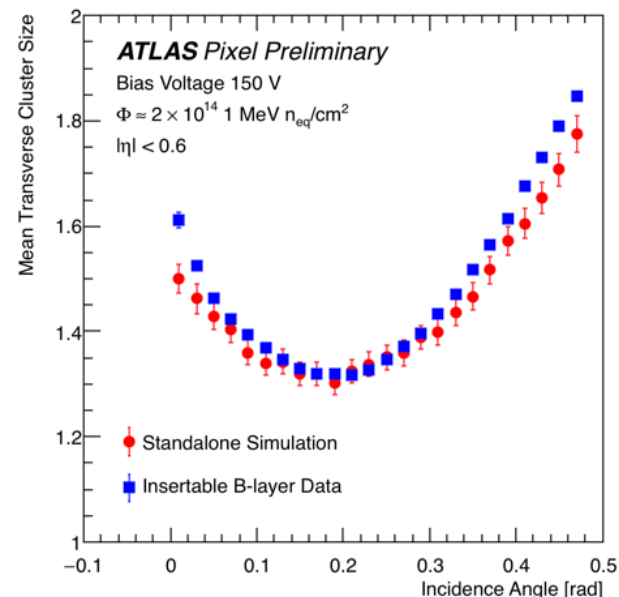
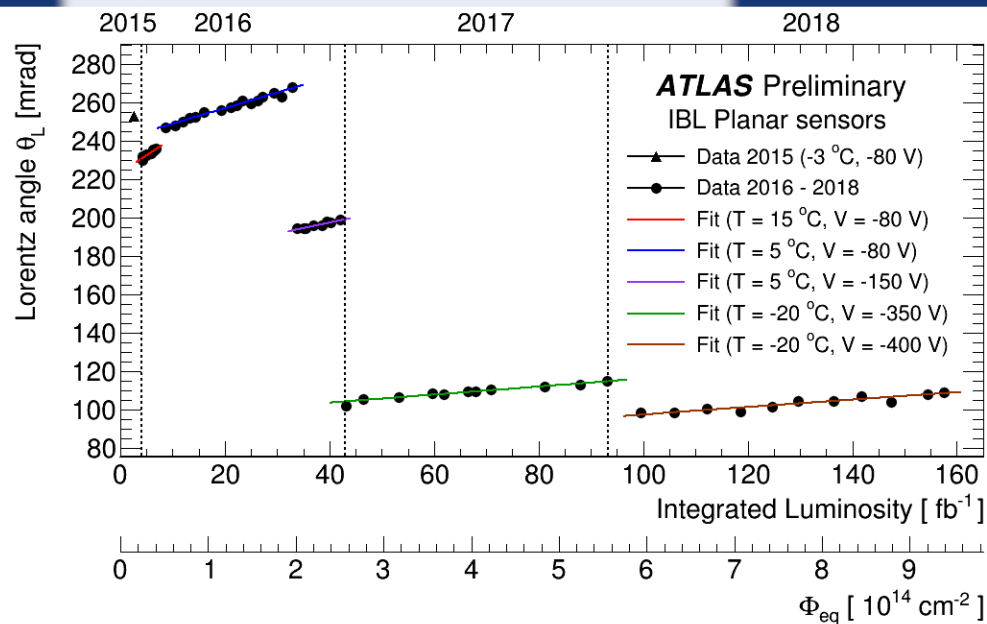
Run 2 Bias Voltage Evolution

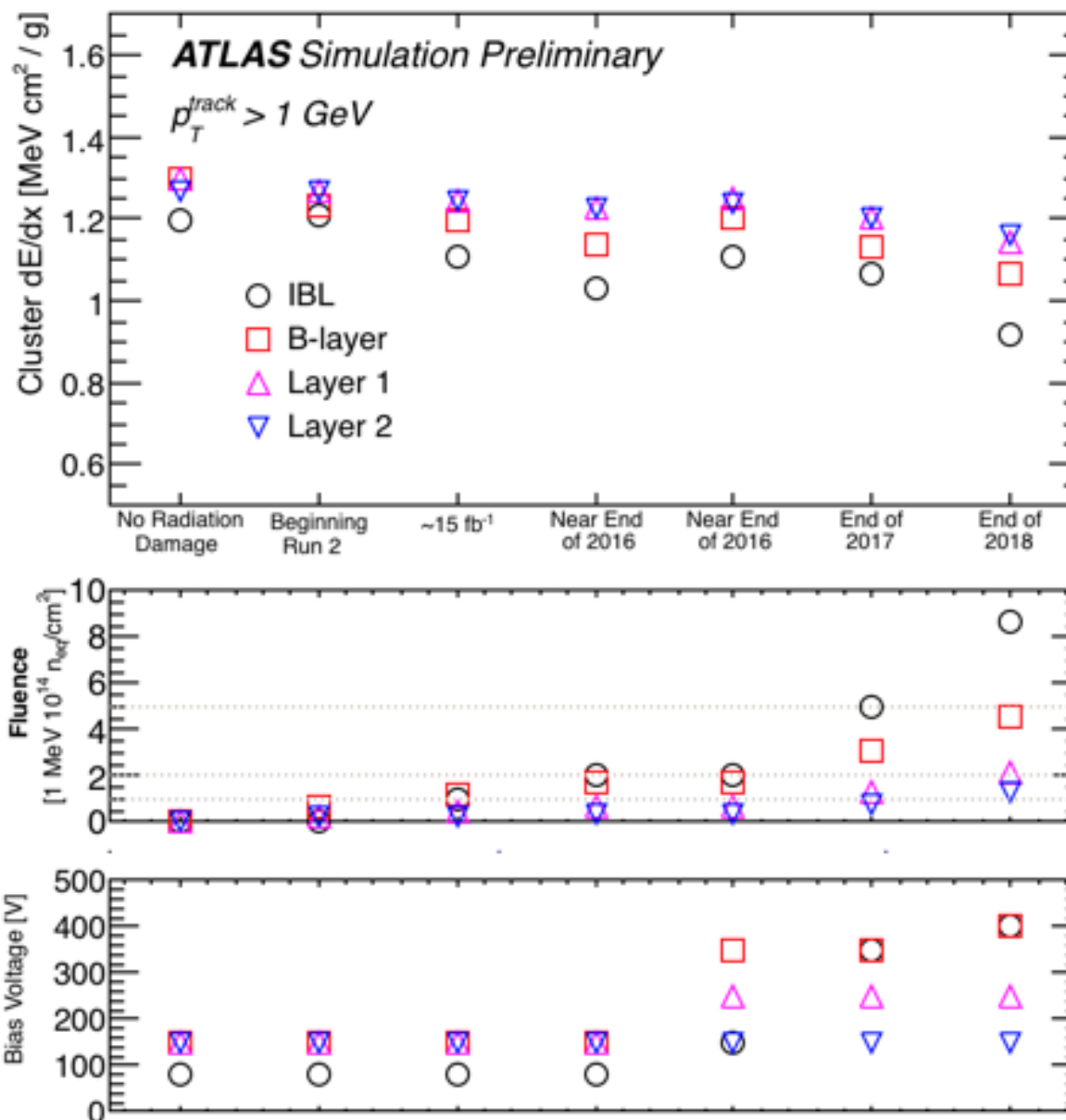
HV	2015	2016	2017	2018
IBL	80V →	150V →	350V →	400V
B-layer	250V	350V	350V	400V
Layer-1	150V	200V	200V	250V
Layer-2	150V	150V	150V	250V
Endcap	150V	150V	150V	250V

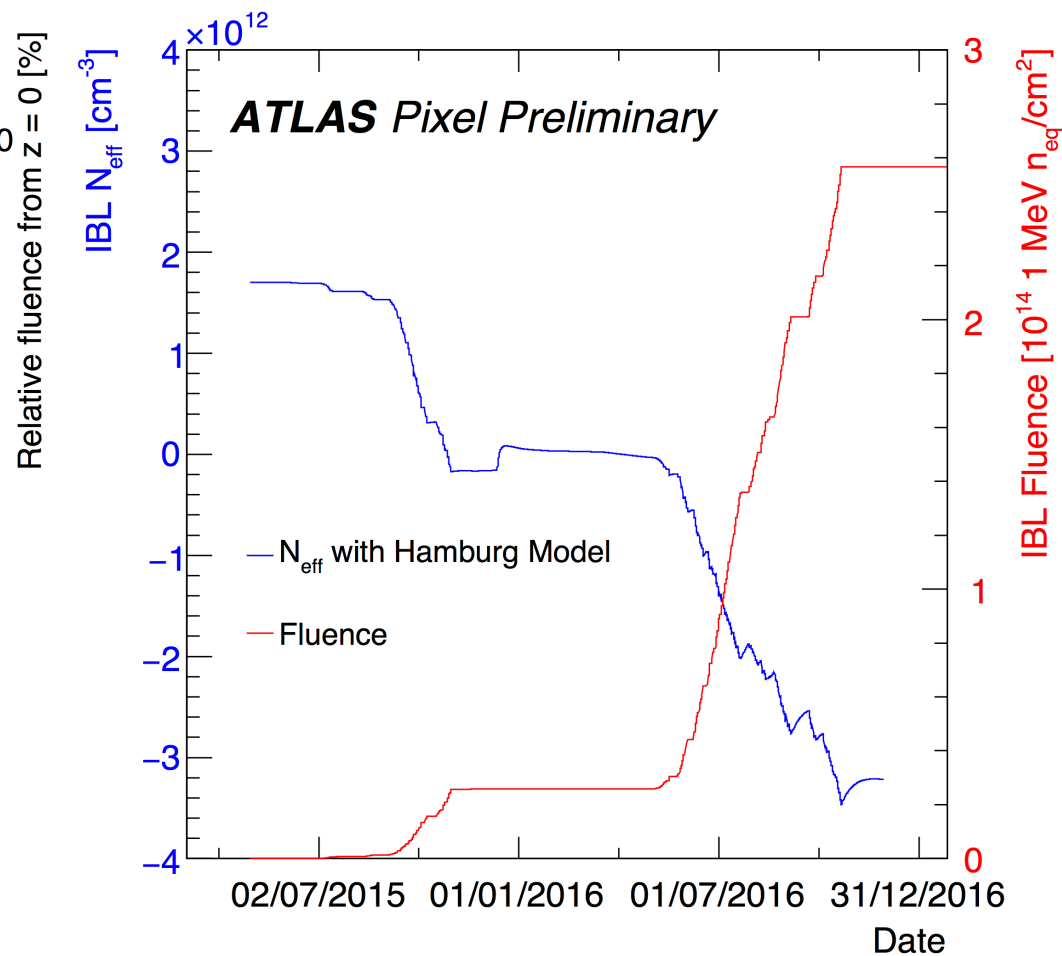
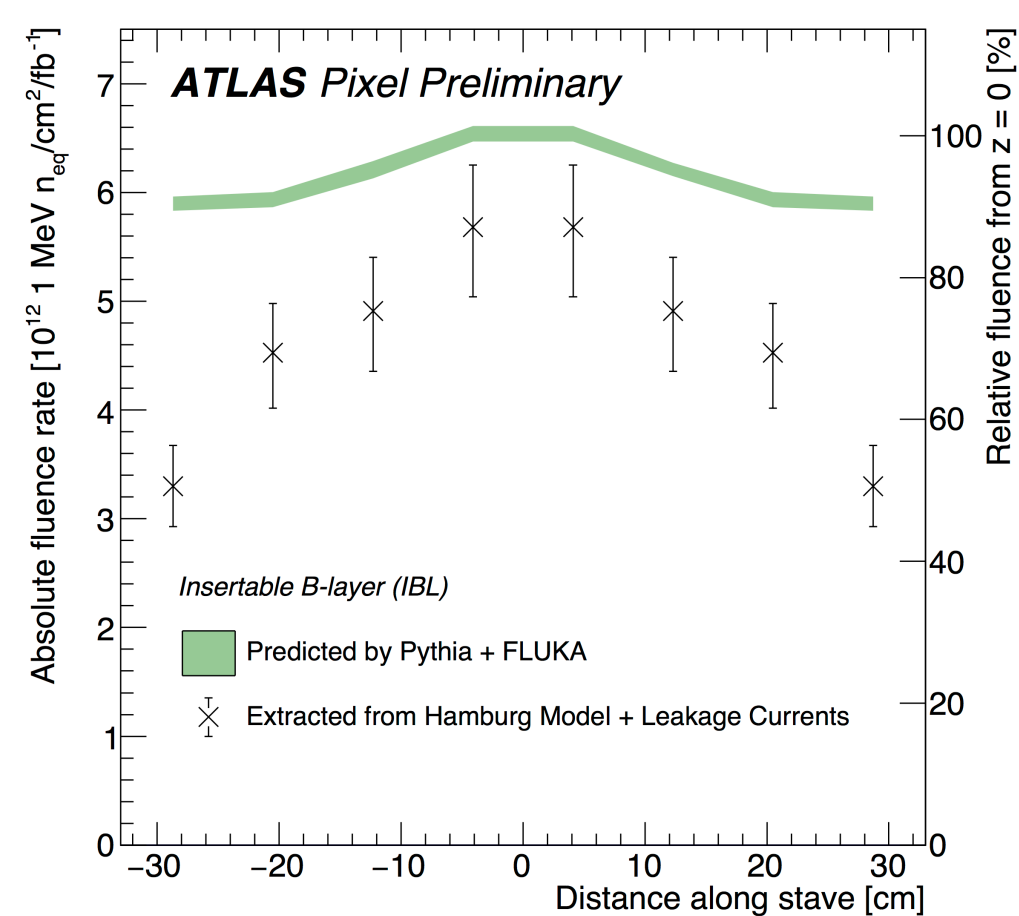
ATLAS Run2 benchmark

L1Trigger = 100 kHz
$\langle \mu \rangle = 60$

→ Module to read-out system bandwidth usage needs to stay within 80%







- HV settings have been adjusted to ensure a well depleted sensor:

→ HV increase in all the layers in 2018!

RUN-2 HV

HV	2015	2016	2017	2018
IBL	80V →	150V →	350V →	400V
B-layer	250V	350V	350V	400V
Layer-1	150V	200V	200V	250V
Layer-2	150V	150V	150V	250V
Endcap	150V	150V	150V	250V

- Radiation damage will be particularly severe in Run 3.
- In order to avoid to run with the detector not fully depleted, Pixel should be kept cooled as long as possible during the LS2 (2 years long).

